

#### **PCTEST**

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## **HEARING AID COMPATIBILITY**

**Applicant Name:** 

Randy Ortanez President

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea Date of Testing: 4/27/2020 - 4/29/2020 Test Site/Location: PCTEST Lab, Columbia, MD, USA Test Report Serial No.: 1M2003200047-02-R1.A3L Date of Issue:

FCC ID: A3LSMA716U

APPLICANT: SAMSUNG ELECTRONICS CO., LTD.

Scope of Test: RF Emissions Testing

Application Type: Certification
FCC Rule Part(s): CFR §20.19(b)
HAC Standard: ANSI C63.19-2011

CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017

285076 D01 HAC Guidance v05

285076 D02 T-Coil testing for CMRS IP v03

5/20/2020

**DUT Type:** Portable Handset **Model:** SM-A716U

**Test Device Serial No.:** Pre-Production Sample [S/N: 06243]

C63.19-2011 HAC Category: M4 (RF EMISSIONS CATEGORY)

Note: This revised Test Report (S/N: 1M2003200047-02-R1.A3L) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

This wireless portable device has been shown to be hearing-aid compatible under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. North America bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.







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## 1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658¹ to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide suffer from hearing loss.

## **Compatibility Tests Involved:**

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid in-vitu

<sup>1</sup> FCC Rule & Order, WT Docket 01-309 RM-8658

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## 2. DUT DESCRIPTION



FCC ID: A3LSMA716U

Manufacturer: Samsung Electronics Co., Ltd.

129, Samsung-ro, Maetan dong,

Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea

Model: SM-A716U

Serial Number: 06243

Antenna Configurations: Internal Antenna
DUT Type: Portable Handset

#### I. Power Reduction for WIFI

This device uses an independent fixed level power reduction mechanism for all WIFI operations during voice or VoIP held to ear scenarios. Reduced powers were used to evaluate for low-power exemption in Section 9.II for WIFI. Detailed descriptions of the power reduction mechanism are included in the operational description.

#### II. LTE Band Selection

This device supports the following pairs of LTE bands with similar frequencies: LTE B4 & B66, B5 & B26, B2 & B25 and B38 & B41. These pairs of LTE bands have the same target powers and share the same transmission paths. Since the supported frequency spans for the smaller LTE bands are completely covered by the larger LTE bands, only the larger LTE bands (LTE B66, B26, B25 & B41) were evaluated for hearing-aid compliance.

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# Table 2-1 A3LSMA716U HAC Air Interfaces

		1	L CIVI, (1 1	OUTIAC All linterlaces		
Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service	
CDMA	835 1900	vo	Yes	Yes: WIFI or BT	CMRS Voice	
	EvDO	VD	No <sup>1</sup>	Yes: WIFI or BT	Google Duo	
GSM	850 1900	VO	Yes	Yes: WIFI or BT	CMRS Voice	
03111	GPRS/EDGE	VD	No <sup>1</sup>	Yes: WIFI or BT	Google Duo	
	850		-			
	1700	VD	No <sup>1</sup>	Yes: WIFI or BT	CMRS Voice	
UMTS	1900					
	HSPA	VD	No <sup>1</sup>	Yes: WIFI or BT	Google Duo	
	680 (B71)		No <sup>1 2</sup>			
	700 (B12)	1				
	780 (B13)	1				
	790 (B14)					
LTE (FDD)	850 (B5)	1		Yes: WIFI or BT		
	850 (B26)	1	No <sup>1</sup>			
	1700 (B4)	VD			VoLTE, Google Duo	
	1700 (B66)	1				
	1900 (B2)					
	1900 (B25)					
	2300 (B30)					
	2500 (B7)					
LTC (TDD)	2600 (B38)	VD	Vos	Voc. WIEL or DT	Vol.TE Coogle Due	
LTE (TDD)	2600 (B41)	VD	Yes	Yes: WIFI or BT	VoLTE, Google Duo	
	680 (n71)		No <sup>1 2</sup>			
NR (FDD)	850 (n5)	VD		Yes: WIFI or BT	Google Due	
ואה (דטט)	1700 (n66)	J	No <sup>1</sup>	Yes: WIFI OF BI	Google Duo	
	1900 (n2)					
NR (TDD)	2600 (n41)	VD	Yes	Yes: WIFI or BT	Google Duo	
	2450					
	5200 (U-NII 1)					
WIFI	5300 (U-NII 2A)	VD	No <sup>1</sup>	Yes: CDMA, GSM, UMTS, LTE, or NR	VoWIFI, Google Duo	
	5500 (U-NII 2C)					
	5800 (U-NII 3)					
ВТ	2450	DT	No	Yes: CDMA, GSM, UMTS, LTE, or NR	N/A	
-			2. LTE B71 and	or MIF and low-power exemption. I NR n71, while outside the scope of ANSI C63.19 ested according to the existing HAC procedures w	•	

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# 3. ANSI/IEEE C63.19 PERFORMANCE CATEGORIES

## I. RF EMISSIONS

The ANSI Standard presents performance requirements for acceptable interoperability of hearing aids with wireless communications devices. When these parameters are met, a hearing aid operates acceptably in close proximity to a wireless communications device.

Category	Telephone RF Parameters			
Near field Category	E-field emissions CW dB(V/m)			
	f < 960 MHz			
M1	50 to 55			
M2	45 to 50			
M3	40 to 45			
M4	< 40			
	f > 960 MHz			
M1	40 to 45			
M2	35 to 40			
М3	30 to 35			
M4	< 30			
Table 3-1 WD near-field categories as defined in ANSI C63.19-2011				

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#### SYSTEM SPECIFICATIONS 4.

#### **EF3DV3 E-Field Probe Description**

Construction: One dipole parallel, two dipoles normal to probe axis

Built-in shielding against static charges

Calibration: In air from 30 MHz to 6.0 GHz

(absolute accuracy ±5.1%, k=2)

30 MHz to > 6 GHz; Frequency:

Linearity: ± 0.2 dB (30 MHz to 6 GHz)

± 0.2 dB in air (rotation around probe axis) Directivity

± 0.4 dB in air (rotation normal to probe axis)

2 V/m to > 1000 V/m Dynamic Range

(M3 or better device readings fall well below diode

compression point)

Linearity: ± 0.2 dB

**Dimensions** Overall length: 337 mm (Tip: 20 mm)

Tip diameter: 4.0 mm (Body: 12 mm)

Distance from probe tip to dipole centers: 1.5 mm



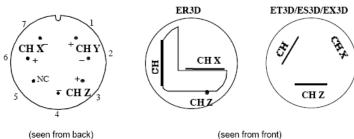
Figure 4-1 E-field Free-space Probe

#### **Probe Tip Description**

HAC field measurements take place in the close near field with high gradients. Increasing the measuring distance from the source will generally decrease the measured field values (in case of the validation dipole approx. 10% per mm).

The electric field probes have an irregular internal geometry because it is physically not possible to have the 3 orthogonal sensors situated with the same center. The effect of the different sensor centers is accounted for in the HAC uncertainty budget ("sensor displacement").

#### Connector Plan



The antistatic shielding inside the probe is connected to the probe connector case.

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#### **Instrumentation Chain**

#### **Equation 1**

## Conversion of Connector Voltage u, to E-Field E,

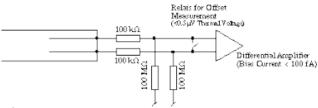
$$E_i = \sqrt{\frac{u_i + (u_i^2 \cdot CF)/(DCP)}{Norm_i \cdot ConvF}}$$

whereby

E<sub>i</sub>: electric field in V/m

u; voltage of channel i at the connector in μV
 Norm; sensitivity of channel i in μV/(V/m)²
 ConvF: enhancement factor in liquid (ConvF=1 for Air)
 DCP: diode compression point in μV
 CF: signal crest factor (peak power/average power)

## Conditions of Calibration

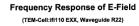


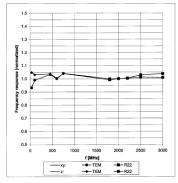
#### Please note:

- a lower input impedance of the amplifier will result in different sensitivity factors Norm, and DCP
- · larger bias currents will cause higher offset

## **Probe Response to Frequency**

The E-field sensors have inherently a very flat frequency response. They are calibrated with a number of frequencies resulting in a common calibration factor, with the frequency behavior documented in the calibration certificate (See also below).





Uncertainty of Frequency Response of E-field: ± 6.3% (k=

Figure 4-2 E-Field Probe Frequency Response

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#### **SPEAG Robotic System**

E-field measurements are performed using the DASY5 automated dosimetric assessment system. The DASY5 is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland and consists of high precision robotics system (Staubli), robot controller, Intel CORE i7 computer, near-field probe, probe alignment sensor, and the HAC phantom. The robot is a six-axis industrial robot performing precise movements to position the probe to the location (points) of maximum electromagnetic field (EMF).



**Figure 4-3** SPEAG Robotic System

#### **System Hardware**

A cell controller system contains the power supply, robot controller, teach pendant (Joystick), and a remote control used to drive the robot motors. The PC consists of the computer with operating system and RF Measurement Software DASY5 v52.8 (with HAC Extension), A/D interface card, monitor, mouse, and keyboard. The Staubli Robot is connected to the cell controller to allow software manipulation of the robot. A data acquisition electronic (DAE) circuit that performs the signal amplification, signal multiplexing, AD-conversion, offset measurements, mechanical surface detection, collision detection, etc. is connected to the Electro-optical coupler (EOC). The EOC performs the conversion from the optical into digital electric signal of the DAE and transfers data to the PC plug-in card.

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#### **System Electronics**

The DAE consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the PC-card is accomplished through an optical downlink for data and status information and an optical uplink for commands and clock lines. The mechanical probe mounting device includes two different sensor systems for frontal and sidewise probe contacts. They are also used for mechanical surface detection and probe collision detection. The robot uses its own controller with a built in VME-bus computer.

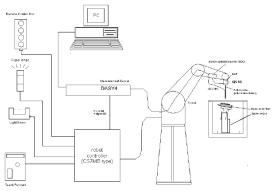


Figure 4-4 SPEAG Robotic System Diagram

#### **DASY5 Instrumentation Chain**

The first step of the evaluation is a linearization of the filtered input signal to account for the compression characteristics of the detector diode. The compensation depends on the input signal, the diode type and the DC-transmission factor from the diode to the evaluation electronics. If the exciting field is pulsed, the crest factor of the signal must be known to correctly compensate for peak power. The formula for each channel can be given as:

$$\begin{aligned} V_i &= U_i + U_i^2 \cdot \frac{cf}{dcp_i} \\ \text{with} \quad V_i &= \text{compensated signal of channel i} & (i = x, y, z) \\ U_i &= \text{input signal of channel i} & (i = x, y, z) \\ cf &= \text{crest factor of exciting field} & (DASY parameter) \\ dcp_i &= \text{diode compression point} & (DASY parameter) \end{aligned}$$

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From the compensated input signals the primary field data for each channel can be evaluated:

E – field  
probes : 
$$E_i = \sqrt{\frac{V_i}{Norm_i \cdot ConvF}}$$

with  $V_i$  = compensated signal of channel i (i = x, y, z)  $Norm_i$  = sensor sensitivity of channel i (i = x, y, z)

 $\mu V/(V/m)^2$  for E-field Probes

ConvF = sensitivity enhancement in solution

 $E_i$  = electric field strength of channel i in V/m

The RSS value of the field components gives the total field strength (Hermitian magnitude):

$$E_{tot} = \sqrt{E_x^2 + E_y^2 + E_z^2}$$

The primary field data are used to calculate the derived field units.

The measurement/integration time per point, as specified by the system manufacturer is >500ms.

The signal response time is evaluated as the time required by the system to reach 90% of the expected final value after an on/off switch of the power source with an integration time of 500ms and a probe response time of <5 ms. In the current implementation, DASY5 waits longer than 100ms after having reached the grid point before starting a measurement, i.e., the response time uncertainty is negligible.

If the device under test does not emit a CW signal, the integration time applied to measure the electric field at a specific point may introduce additional uncertainties due to the discretization. The tolerances for the different systems had the worst-case of 2.6%.

#### **Environmental Conditions**

Environmental conditions such as temperature and relative humidity are monitored to ensure there are no impacts on system specifications. Proper voltage and power line frequency conditions are maintained with three phase power sources. Environmental noise and reflections are monitored through system checks.

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## 5. TEST PROCEDURE

## I. RF EMISSIONS

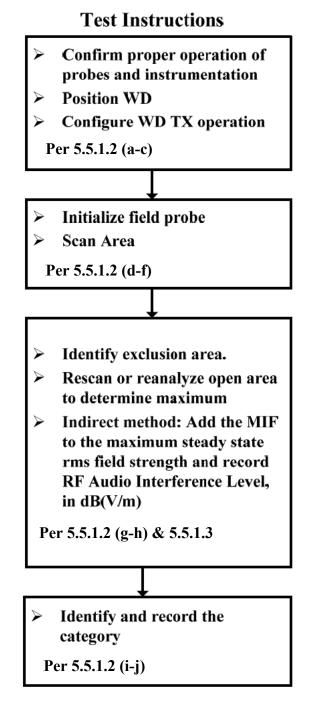


Figure 5-1 RF Emissions Flow Chart

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#### **Test Setup**

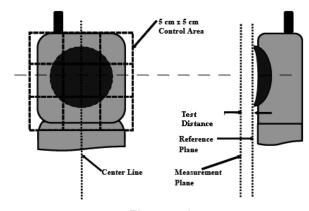


Figure 5-2
E-Field Emissions Test Setup Diagram (See Test Photographs for actual WD scan grid overlay)

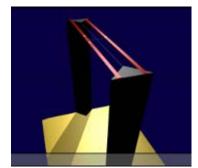


Figure 5-3 HAC Phantom

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#### **RF Emissions Test Procedure:**

The following illustrate a typical RF emissions test scan over a wireless communications device:

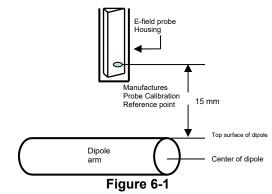
- 1. Proper operation of the field probe, probe measurement system, other instrumentation, and the positioning system was confirmed.
- 2. WD is positioned in its intended test position, acoustic output point of the device perpendicular to the field probe.
- 3. The WD operation for maximum rated RF output power was configured and confirmed with the base station simulator, at the test channel and other normal operating parameters as intended for the test. The battery was ensured to be fully charged before each test.
- 4. The center sub-grid was centered over the center of the acoustic output (also audio band magnetic output, if applicable). The WD audio output was positioned tangent (as physically possible) to the measurement plane.
- 5. A surface calibration was performed before each setup change to ensure repeatable spacing and proper maintenance of the measurement plane using the HAC Phantom.
- 6. The measurement system measured the field strength at the reference location.
- 7. Measurements at 2mm or 5mm increments in the 5 x 5 cm region were performed at a distance 15 mm from the center point of the probe measurement element to the WD. Of the 9 subgrids (see Figure 5-2), 3 contiguous subgrids may be excluded from the measurement in order to account for localized areas of higher field intensities. The center subgrid containing the acoustic output or audio band magnetic output may not excluded. A 360° rotation about the azimuth axis at the maximum interpolated position was measured. For the worst-case condition, the peak reading from this rotation was used in re-evaluating the HAC category.
- 8. The system performed a drift evaluation by measuring the field at the reference location. If the power drift deviated by more than 5%, the HAC test and drift measurements were repeated.

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## I. System Check Parameters

The input signal was an un-modulated continuous wave. The following points were taken into consideration in performing this check:

- Average Input Power P = 100mW RMS (20dBm RMS) after adjustment for return loss
- The test fixture must meet the 2 wavelength separation criterion
- The proper measurement of the 15 mm probe to dipole separation, which is measured from top surface of the dipole to the calibration reference point of the sensor, defined by the probe manufacturer is shown in the following diagram:



Separation Distance from Dipole to Field Probe

RF power was recorded using both an average reading meter and a peak reading meter. Readings of the probe are provided by the measurement system.

To assure proper operation of the near-field measurement probe the input power to the dipole shall be commensurate with the full rated output power of the wireless device [e.g. - for a cellular phone wireless device the average peak antenna input power will be on the order of 100mW (20dBm) RMS] after adjustment for any mismatch.

### II. Validation Procedure

A dipole antenna meeting the requirements given in C63.19 was placed in the position normally occupied by the WD.

The length of the dipole was scanned, and the average peak value was recorded.

#### **Measurement of CW**

Using the near-field measurement system, scan the antenna over the radiating dipole and record the greatest field reading observed. Due to the nature of E-fields about free-space dipoles, the two E-field peaks measured over the dipole are averaged to compensate for non-parallelity of the setup (see

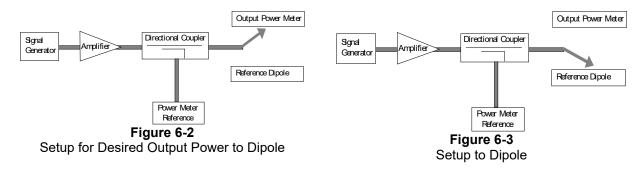
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manufacturer method on dipole calibration certificates, page 2). Field strength measurements shall be made only when the probe is stationary.

RF power was recorded using both an average and a peak power reading meter.



Using this setup configuration, the signal generator was adjusted for the desired output power (100mW) at a specified frequency. The reference power from the coupled port of the directional coupler is recorded. Next, the output cable is connected to the reference dipole, as shown in Figure 6-3.

The input signal level was adjusted until the reference power from the coupled port of the directional coupler was the same as previously recorded, to compensate for the impedance mismatch between the output cable and the reference dipole. To assure proper operation of the near-field measurement probe the input power to the reference dipole was verified to the full rated output power of the wireless device. The dipole was secured in a holder in a manner to meet the 20 dB reflection. The near-field measurement probe was positioned over the dipole. The antenna was scanned over the appropriate sized area to cover the dipole from end to end. SPEAG uses 2D interpolation algorithms between the measured points. Please see below two dimensional plots showing that the interpolated values interpolate smoothly between 5mm steps for a free-space RF dipole:



**Figure 6-4** 2-D Raw Data from scan along dipole axis

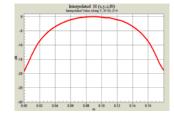
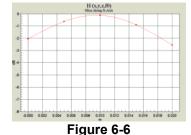


Figure 6-5
2-D Interpolated points from scan along dipole axis



2-D Raw Data from scan along transverse axis



2-D Interpolated points from scan along transverse axis

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## **III. System Check Results**

## **Validation Results**

Date	Frequency (MHz)	Probe S/N	DAE S/N	Dipole S/N	Input Power (dBm)	E-field Result (V/m)	Target Field (V/m)	% Deviation
	835			1003	20.0	104.5	105.2	-0.7%
4/27/2020	1880	4035	665	1137	20.0	88.5	87.8	0.8%
	2600			1012	20.0	87.1	85.2	2.2%

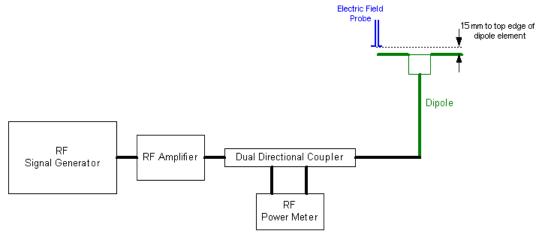


Figure 6-8 System Check Setup

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## 7. MODULATION INTERFERENCE FACTOR

## I. Measuring Modulation Interference Factors

For any specific fixed and repeatable modulated signal, a modulation interference factor (MIF, expressed in dB) may be determined that relates its interference potential to its steady-state RMS signal level or average power level. This factor is a function only of the audio-frequency amplitude modulation characteristics of the signal and is the same for field-strength and conducted power measurements. The MIF is valid only for a specific repeatable audio-frequency amplitude modulation characteristic; any change in modulation characteristic requires determination and application of a new MIF.

The MIF may be determined using a radiated RF field or a conducted RF signal:

- a. Using RF illumination or conducted coupling, apply the specific modulated signal in question to the measurement system at a level within its confirmed operating dynamic range.
- b. Measure the steady-state RMS level at the output of the fast probe or sensor.
- c. Measure the steady-state average level at the weighting output.
- d. Without changing the square-law detector or weighting system, and using RF illumination or conducted coupling, substitute for the specific modulated signal a 1 kHz, 80% amplitude modulated carrier at the same frequency and adjust its strength until the level at the weighting output equals the step c) measurement.
- e. Without changing the carrier level from step d), remove the 1 kHz modulation and again measure the steady-state RMS level indicated at the output of the fast probe or sensor.
- f. The MIF for the specific modulation characteristic is provided by the ratio of the step e) measurement to the step b) measurement, expressed in dB (20 × log[(step e)/(step b)]).

The following procedure was used to measure the MIF using the SPEAG Audio Interference Analyzer (AIA), Type No: SE UMS 170 CB, Serial No.: 1010:

- 1. The device was placed into a simulated call using a base station simulator or set to transmit using test software for a given mode.
- 2. The device was then set to continuously transmit at maximum power.
- 3. Using a coupler if needed, the device output signal was connected to the RF In port of the AIA, which was connected to a desktop computer. Alternatively, a radiated RF signal may be used with the AIA's built-in antenna.
- 4. The MIF measurement procedure in the DASY software was run, and the resulting MIF value was recorded.
- 5. Steps 1-4 were repeated for all CMRS air interfaces, frequency bands, and modulations.

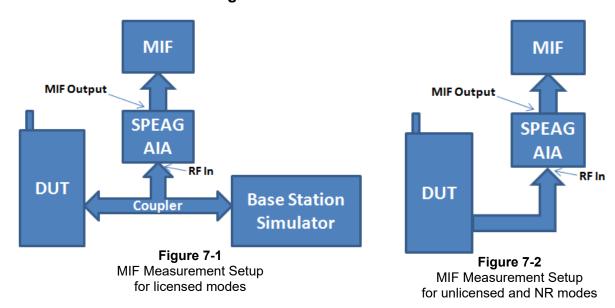
The modulation interference factors obtained were applied to readings taken of the actual wireless device in order to obtain an accurate audio interference level reading using the formula:

#### Audio Interference Level [dB(V/m)] = 20 \* log[Raw Field Value (V/m)] + MIF (dB)

Because the MIF value is output power independent, MIF values for a given mode should be constant across all devices; however, per C63.19-2011 §D.7, MIF values should be measured for each device being evaluated. The voice modes for this device have been investigated in this section of the report.

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## II. MIF Measurement Block Diagrams



## **III. Measured Modulation Interference Factors:**

Table 7-1 CDMA Modulation Interference Factors<sup>1</sup>

	OBINIT MODULATION INTERPORT ACTOR								
2.0	-	Cell				PCS			
IVIC	ode	564	1013	384	777	25	600	1175	
	RC1/SO3	3.04	3.01	3.05	3.01	3.01	3.02	3.05	
CDMA	RC1/SO55	-19.74	-19.68	-19.82	-19.80	-20.06	-20.08	-20.02	
	EvDO	-19.35	-19.42	-19.45	-19.54	-19.48	-19.46	-19.49	

Table 7-2 GSM Modulation Interference Factors<sup>1</sup>

GSW Woddiation interference Factors									
N/a	ode	GSM850			GSM850 GSM1900				
IVIC	Jue	128	190	251	512 661 810				
GSM	Voice	3.54	3.54	3.54	3.53	3.54	3.53		
GSW	EDGE	3.74	3.76	3.75	3.73	3.71	3.72		

Table 7-3 UMTS Modulation Interference Factors<sup>1</sup>

24.0	a de		UMTS V		UMTS IV			UMTS II		
IVIC	Mode		4183	4233	1312	1412	1513	9262	9400	9538
	12.2 kbps RMC	-24.43	-23.90	-21.08	-23.99	-24.01	-23.58	-25.78	-24.13	-25.29
UMTS	12.2 kbps AMR	-24.57	-25.01	-22.27	-24.39	-24.37	-23.64	-24.52	-24.50	-25.58
	HSUPA Subtest1	-23.67	-24.08	-22.04	-23.29	-23.45	-23.24	-23.57	-23.57	-23.36

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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**Table 7-4**LTE FDD Modulation Interference Factors<sup>1,2</sup>

		1 L 1 D 10	IIICOITOIOIC	C I aciois			
LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
71	680.5	133297	20	16QAM	1	0	-9.74
66	1745.0	132322	20	16QAM	1	0	-10.19
25	1882.5	26365	20	16QAM	1	0	-9.69
7	2535.0	21100	20	16QAM	1	0	-10.13
26	831.5	26865	15	16QAM	1	0	-9.81
12	707.5	23095	10	16QAM	1	0	-9.98
13	782.0	23230	10	16QAM	1	0	-11.01
14	793.0	23330	10	16QAM	1	0	-9.79
30	2310.0	27710	10	16QAM	1	0	-10.62
25	1882.5	26365	20	QPSK	1	0	-15.02
25	1882.5	26365	20	64QAM	1	0	-10.16
25	1882.5	26365	20	16QAM	1	50	-9.71
25	1882.5	26365	20	16QAM	1	99	-10.91
25	1882.5	26365	20	16QAM	50	0	-16.78
25	1882.5	26365	20	16QAM	100	0	-17.84
25	1882.5	26365	15	16QAM	1	0	-9.76
25	1882.5	26365	10	16QAM	1	0	-9.81
25	1882.5	26365	5	16QAM	1	0	-10.82
25	1882.5	26365	3	16QAM	1	0	-9.75
25	1882.5	26365	1.4	16QAM	1	0	-10.69
25	1860.0	26140	20	16QAM	1	0	-10.27
25	1905.0	26590	20	16QAM	1	0	-9.91

<sup>&</sup>lt;sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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O GOOD BOTTOT				DE\/ 0 = 1

 $<sup>^2</sup>$  Note: All FDD LTE bands were found to have substantially similar MIF values given similar RB, BW, and modulation configurations.

**Table 7-5**LTE TDD B41 Power Class 3 Modulation Interference Factors<sup>1,2</sup>

	ETE TOD D411 OWER Class 5 Woodclattor Interference Lactors									
LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]			
41	2593.0	40620	20	16QAM	1	0	1.45			
41	2593.0	40620	20	QPSK	1	0	1.40			
41	2593.0	40620	20	64QAM	1	0	1.37			
41	2593.0	40620	20	16QAM	1	50	1.40			
41	2593.0	40620	20	16QAM	1	99	1.40			
41	2593.0	40620	20	16QAM	50	0	1.33			
41	2593.0	40620	20	16QAM	100	0	1.33			
41	2593.0	40620	15	16QAM	1	0	1.36			
41	2593.0	40620	10	16QAM	1	0	1.52			
41	2593.0	40620	5	16QAM	1	0	1.38			
41	2506.0	39750	10	16QAM	1	0	1.51			
41	2549.5	40185	10	16QAM	1	0	1.41			
41	2636.5	41055	10	16QAM	1	0	1.39			
41	2680.0	41490	10	16QAM	1	0	1.50			

**Table 7-6**LTE TDD B41 Power Class 2 Modulation Interference Factors<sup>1,2</sup>

	LTL TDD D411 Ower Class 2 Modulation Interference Lactors							
LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]	
41	2593.0	40620	20	16QAM	1	0	1.43	
41	2593.0	40620	20	QPSK	1	0	1.42	
41	2593.0	40620	20	64QAM	1	0	1.42	
41	2593.0	40620	20	16QAM	1	50	1.45	
41	2593.0	40620	20	16QAM	1	99	1.44	
41	2593.0	40620	20	16QAM	50	0	1.38	
41	2593.0	40620	20	16QAM	100	0	1.38	
41	2593.0	40620	15	16QAM	1	36	1.57	
41	2593.0	40620	10	16QAM	1	25	1.56	
41	2593.0	40620	5	16QAM	1	12	1.45	
41	2506.0	39750	15	16QAM	1	36	1.56	
41	2549.5	40185	15	16QAM	1	36	1.47	
41	2636.5	41055	15	16QAM	1	36	1.43	
41	2680.0	41490	15	16QAM	1	36	1.57	

**Table 7-7**LTE TDD Uplink Carrier Aggregation Modulation Interference Factor<sup>1,3</sup>

ETE TBB Opinik Gamer Aggregation Medalation Interiored Lactor															
PCC							scc								
Combination	PCC Band	PCC Bandwidth [MHz]	PCC (UL/DL) Channel	PCC (UL/DL) Frequency [MHz]	Modulation	PCC UL# RB	PCC UL RB Offset	SCC Band	SCC Bandwidth [MHz]	SCC (UL/DL) Channel	SCC (UL/DL) Frequency [MHz]		SCC UL# RB	SCC UL RB Offset	MIF (dB)
CA_41C (PC3)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	1.41
CA_41C (PC2)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	1.47

<sup>&</sup>lt;sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>&</sup>lt;sup>3</sup> Note: LTE TDD ULCA was evaluated to ensure LTE TDD standalone was the worst-case scenario. The configuration in Table 7-7 was determined from Tables 7-5 & 7-6 and satisfies the configuration requirements as defined in 3GPP 36.101. These MIFs were evaluated with UL-DL Configuration 2 for Power Class 3 and Power Class 2 LTE TDD

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<sup>&</sup>lt;sup>2</sup> Note: LTE TDD MIFs were taken using UL-DL Configuration 2 for both Power Class 3 and Power Class 2. More information about the chosen UL-DL Configuration can be found in Section 10.

**Table 7-8**NR FDD Modulation Interference Factors<sup>1</sup>

NR Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	MIF [dB]
n71	680.5	136100	20	DFT-s-OFDM	16QAM	1	1	-11.70
n5	836.5	167300	20	DFT-s-OFDM		1	1	-12.54
n66	1745.0	349000	20	DFT-s-OFDM	16QAM	1	1	-12.01
n2	1880.0	376000	20	DFT-s-OFDM	16QAM	1	1	-11.24
n2	1880.0	376000	20	DFT-s-OFDM	64QAM	1	1	-9.38
n2	1880.0	376000	20	DFT-s-OFDM	256QAM	1	1	-11.28
n2	1880.0	376000	20	DFT-s-OFDM	π/2-BPSK	1	1	-17.14
n2	1880.0	376000	20	DFT-s-OFDM	QPSK	1	1	-15.64
n2	1880.0	376000	20	CP-OFDM	16QAM	1	1	-9.44
n2	1880.0	376000	20	CP-OFDM	64QAM	1	1	-10.34
n2	1880.0	376000	20	CP-OFDM	256QAM	1	1	-10.18
n2	1880.0	376000	20	CP-OFDM	QPSK	1	1	-12.75
n2	1880.0	376000	20	DFT-s-OFDM	64QAM	1	53	-11.53
n2	1880.0	376000	20	DFT-s-OFDM	64QAM	1	104	-11.47
n2	1880.0	376000	20	DFT-s-OFDM	64QAM	50	0	-15.91
n2	1880.0	376000	20	DFT-s-OFDM	64QAM	100	0	-16.20
n2	1880.0	376000	15	DFT-s-OFDM	64QAM	1	0	-11.46
n2	1880.0	376000	10	DFT-s-OFDM	64QAM	1	0	-9.40
n2	1880.0	376000	5	DFT-s-OFDM	64QAM	1	0	-12.99
n2	1860.0	372000	20	DFT-s-OFDM	64QAM	1	0	-9.74
n2	1900.0	380000	20	DFT-s-OFDM	64QAM	1	0	-9.68

**Table 7-9**NR TDD Modulation Interference Factors<sup>1</sup>

NR Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	MIF [dB]
n41	2593.0	518598	20	DFT-s-OFDM	16QAM	1	1	1.36
n41	2593.0	518598	20	DFT-s-OFDM	π/2-BPSK	1	1	1.46
n41	2593.0	518598	20	DFT-s-OFDM	QPSK	1	1	1.37
n41	2593.0	518598	20	DFT-s-OFDM	64QAM	1	1	1.54
n41	2593.0	518598	20	DFT-s-OFDM	256QAM	1	1	1.36
n41	2593.0	518598	20	CP-OFDM	QPSK	1	1	1.19
n41	2593.0	518598	20	CP-OFDM	16QAM	1	1	1.32
n41	2593.0	518598	20	CP-OFDM	64QAM	1	1	1.22
n41	2593.0	518598	20	CP-OFDM	256QAM	1	1	1.10
n41	2593.0	518598	20	DFT-s-OFDM	64QAM	1	137	1.52
n41	2593.0	518598	20	DFT-s-OFDM	64QAM	1	271	1.50
n41	2593.0	518598	20	DFT-s-OFDM	64QAM	135	0	1.41
n41	2593.0	518598	20	DFT-s-OFDM	64QAM	270	0	1.41
n41	2593.0	518598	90	DFT-s-OFDM	64QAM	1	1	1.56
n41	2593.0	518598	80	DFT-s-OFDM	64QAM	1	1	1.55
n41	2593.0	518598	60	DFT-s-OFDM	64QAM	1	1	1.51
n41	2593.0	518598	50	DFT-s-OFDM	64QAM	1	1	1.54
n41	2593.0	518598	40	DFT-s-OFDM	64QAM	1	1	1.52
n41	2593.0	518598	20	DFT-s-OFDM	64QAM	1	1	1.47
n41	2541.0	508200	90	DFT-s-OFDM	64QAM	1	1	1.53
n41	2644.98	528996	90	DFT-s-OFDM	64QAM	1	1	1.52

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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Table 7-10

802.11b (2.4GHz, SISO) Modulation Interference Factors<sup>1,2</sup>

802.11b MIF Measurements [dB]							
Mode	Data Rate [Mbps]						
	1	2	5.5	11			
802.11b	-8.81	-9.93	-9.23	-8.67			

#### **Table 7-11**

802.11g (2.4GHz, SISO) Modulation Interference Factors<sup>1,2</sup>

	802.11g MIF Measurements [dB]								
Mode		Data Rate [Mbps]							
	6	9	12	18	24	36	48	54	
802.11g	-9.76	-8.87	-8.80	-8.51	-8.33	-8.64	-8.92	-9.10	

#### **Table 7-12**

802.11n (2.4GHz, SISO) Modulation Interference Factors<sup>1,2</sup>

_	302.1 m (2.131.2, 3133) madalatism meneralisa rasters												
				802.11n (2	.4GHz) MIF	- Measurei	ments [dB]						
	Mode		MCS Index										
		0	1	2	3	4	5	6	7				
Ī	802.11n	-8.98     -8.66     -8.49     -8.46     -8.37     -9.03     -9.11     -9.00											

#### **Table 7-13**

802.11a (5GHz, 20MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

		,	802.1	1a MIF Mea	surements	s [dB]						
Mode		Data Rate [Mbps]										
	6	9	12	18	24	36	48	54				
802.11a	-11.63     -10.85     -10.38     -9.70     -9.26     -9.56     -10.05     -10.3											

#### **Table 7-14**

802.11n (5GHz, 20MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

	002.1111	(00112, 20		ologi Mod	alation into	TICICITOC I C	101010				
		20MH	<b>Iz BW 802</b>	.11n (5GHz	z) MIF Mea	surements	[dB]				
Mode MCS Index											
	0	1	2	3	4	5	6	7			
802.11n	-11.84 -10.73 -9.82 -9.53 -9.69 -10.10 -10.32 -10.62										

#### **Table 7-15**

802.11ac (5GHz, 20MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

		2	20MHz BW	802.11ac	(5GHz) MII	F Measure	ments [dB]	]					
Mode		MCS Index											
	0	1	2	3	4	5	6	7	8				
802.11ac	ic -11.80 -10.64 -9.77 -9.41 -9.65 -10.05 -10.24 -10.55 -10.84												

<sup>&</sup>lt;sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>&</sup>lt;sup>2</sup> Note: WIFI MIF values were found to be independent of the transmit channel.

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# **Table 7-16**802.11n (5GHz, 40MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

		40MH	z BW 802.	.11n (5GHz	z) MIF Mea	surements	[dB]					
Mode	MCS Index											
	0	1	2	3	4	5	6	7				
802.11n	-9.69	-9.69     -8.95     -9.18     -9.64     -10.77     -11.82     -12.03     -12.26										

#### **Table 7-17**

802.11ac (5GHz, 40MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

		,	40MH:	z BW 802.	11ac (5GH	z) MIF Mea	surement	s [dB]					
Mode		MCS Index											
	0	1	2	3	4	5	6	7	8	9			
802.11ac	ac -9.68 -8.83 -9.15 -9.57 -10.67 -11.70 -12.02 -12.16 -13.75 -13												

#### **Table 7-18**

802.11ac (5GHz, 80MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

		,	80MH	z BW 802.	11ac (5GH	z) MIF Mea	surements	s [dB]					
Mode		MCS Index											
	0	1	2	3	4	5	6	7	8	9			
802.11ac	-9.25 -10.00 -10.97 -11.91 -12.75 -13.47 -13.77 -13.98 -14.39 -14.63												

<sup>&</sup>lt;sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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<sup>&</sup>lt;sup>2</sup> Note: WIFI MIF values were found to be independent of the transmit channel.

## 8. RF CONDUCTED POWER MEASUREMENTS

## I. Procedures Used to Establish RF Signal for HAC Testing

The handset was configured to transmit the required air interface in a shielded chamber. Measurements were taken with a fully charged battery.

#### II. HAC Measurement Conditions

#### **Output Power Verification**

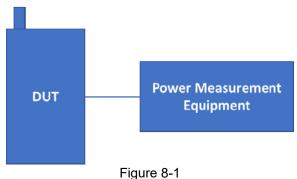
Maximum output power is verified on the High, Middle and Low channels for all applicable air interfaces for which full testing scans are required. Modes which are exempted from full testing according to Section 9 of this report have only their conducted power targets listed below, not measured values. See Table 8-1 for air interface specific settings of transmit power parameters. See Table 9-1 for more information regarding which modes required full testing and had conducted power measurements taken.

Table 8-1
Power Control Parameters and Settings by Air Interface

Air Interface:	Parameter Name:	Parameter Set To:			
CDMA	Power Control Bits	"All Up"			
GSM	PCL	GSM850: "5"; GSM1900: "0"			
UMTS	TPC	"All 1's"			
LTE	TPC	"Max Power"			
NR	PLS	Mfr Specified			
WIFI	PLS	Mfr Specified			

## III. Setup Used to Measure RF Conducted Powers

The general setup for conducted power is shown in Figure 8-1 below. The power measurement equipment could be a base station simulator, signal analyzer, or power meter depending on the applicable air interface.



Power Measurement Setup

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## **IV. CDMA Conducted Powers**

Band	Channel	Rule Part	Frequency	SO2 [dBm]	SO2 [dBm]	SO2 [dBm]	SO55 [dBm]	SO55 [dBm]	SO75 [dBm]	SO9 [dBm]	SO9 [dBm]	SO3 [dBm]	SO3 [dBm]	SO3 [dBm]	1x EvDO Rev. A [dBm]
	F-RC		MHz	RC1	RC3	RC4	RC1	RC3	RC11	RC2	RC5	RC1	RC3	RC4	(RETAP)
Cellular	564	90S	820.1	24.72	24.73	24.71	24.73	24.72	24.82	24.73	24.72	24.73	24.72	24.73	25.89
	1013	22H	824.7	24.67	24.72	24.73	24.72	24.71	24.78	24.70	24.69	24.71	24.70	24.69	25.90
Cellular	384	22H	836.52	24.62	24.63	24.65	24.64	24.65	24.94	24.64	24.66	24.64	24.66	24.67	25.83
	777	22H	848.31	24.67	24.65	24.61	24.62	24.68	24.76	24.67	24.69	24.69	24.68	24.69	24.38
	25	24E	1851.25	24.40	24.39	24.36	24.40	24.39	24.36	24.39	24.38	24.37	24.38	24.40	24.15
PCS	600	24E	1880	24.20	24.18	24.22	24.19	24.14	24.19	24.18	24.19	24.18	24.19	24.18	24.01
	1175	24E	1908.75	24.05	24.08	24.08	24.06	24.08	24.23	24.06	24.07	24.08	24.07	24.08	24.10

## V. GSM Conducted Powers

Band	Channel	GSM [dBm] CS (1 Slot)	EDGE [dBm] 1 Tx Slot
	128	32.69	27.12
GSM 850	190	32.55	26.94
	251	32.59	27.04
	512	30.04	26.22
GSM 1900	661	29.38	26.06
	810	29.92	26.03

## **VI. UMTS Target Powers**

Table 8-2 UMTS Conducted Power Targets

		Modulated Average (dBm)					
Mode / Band		3GPP WCDMA	3GPP HSDPA	3GPP HSUPA	3GPP DC- HSDPA		
UMTS Band 5 (850 MHz)	Maximum	25.0	24.0	24.0	24.0		
OIVITS Ballu 5 (650 IVITIZ)	Nominal	24.0	23.0	23.0	23.0		
UMTS Band 4 (1750 MHz)	Maximum	25.0	24.0	24.0	24.0		
01V113 Ballu 4 (1/30 IVITZ)	Nominal	24.0	23.0	23.0	23.0		
LIMTS Band 2 (1000 MHz)	Maximum	24.0	23.0	23.0	23.0		
UMTS Band 2 (1900 MHz)	Nominal	23.0	22.0	22.0	22.0		

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#### LTE FDD Target Powers VII.

Table 8-3 **LTE FDD Conducted Power Targets** 

	DD Conducted Pov	Modulated Average
Mode / Band	d	(dBm)
	Maximum	25.5
LTE Band 71	Nominal	24.5
	Maximum	25.5
LTE Band 12	Nominal	24.5
	+	
LTE Band 13	Maximum	25.5
	Nominal	24.5
LTE Band 14	Maximum	25.5
	Nominal	24.5
LTE Band 5 (Cell)	Maximum	25.5
ETE Bana 3 (een)	Nominal	24.5
LTE Band 26 (Cell)	Maximum	25.5
LTE Ballu 20 (Cell)	Nominal	24.5
LTE Donal CC (AVA/C)	Maximum	25.0
LTE Band 66 (AWS)	Nominal	24.0
1.TE D. 1.4 (A)A(C)	Maximum	25.0
LTE Band 4 (AWS)	Nominal	24.0
177 0 107 (200)	Maximum	24.5
LTE Band 25 (PCS)	Nominal	23.5
	Maximum	24.5
LTE Band 2 (PCS)	Nominal	23.5
	Maximum	24.0
LTE Band 30	Nominal	23.0
	Maximum	24.0
LTE Band 7	Nominal	22.0
	INOITHIAI	22.0

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## VIII. LTE TDD Conducted and Target Powers

## a. LTE Band 41 - Power Class 3

Table 8-4 LTE Band 41 (2593.0MHz) Conducted Powers – 20MHz Bandwidth

				<u>,                                      </u>	LTE Band 41	OWC13 - 20			
		ı		. 2	0 MHz Bandwidth				
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	onducted Power [dE	im]			
	1	0	22.88	23.05	22.81	23.00	22.98		0
	1	50	22.78	23.02	23.34	23.14	22.99	0	0
	1	99	22.92	22.96	22.80	22.56	22.94		0
QPSK	50	0	21.92	22.17	22.33	22.26	22.06		1
	50	25	22.05	22.19	22.43	22.21	22.29	0-1	1
	50	50	21.98	22.14	22.41	22.26	22.21	0-1	1
	100	0	21.98	22.11	22.34	22.15	22.25		1
	1	0	22.10	22.39	22.23	22.26	21.96		1
	1	50	22.07	22.27	22.60	22.34	22.33	0-1	1
	1	99	22.17	22.35	22.27	21.91	22.10		1
16QAM	50	0	20.99	21.22	21.39	21.32	21.13		2
	50	25	21.11	21.20	21.47	21.32	21.33	0-2	2
	50	50	21.10	21.13	21.51	21.17	21.30	0-2	2
	100	0	21.09	21.13	21.37	21.24	21.27		2
	1	0	21.09	21.24	21.12	21.21	20.93	]	2
	1	50	21.10	21.13	21.49	21.44	21.41	0-2	2
	1	99	21.08	21.05	21.09	20.91	21.32		2
64QAM	50	0	20.38	20.35	20.42	20.44	20.23		3
	50	25	20.46	20.41	20.57	20.50	20.41	0-3	3
	50	50	20.47	20.31	20.49	20.31	20.47	0-3	3
	100	0	20.39	20.21	20.41	20.36	20.28		3

Table 8-5 LTE Band 41 (2593.0MHz) Conducted Powers – 15MHz Bandwidth

			(=00	·······-, · · ·	LTE Band 41		mile Balla		
				1	5 MHz Bandwidth				
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	nducted Power [dE	Bm]			
	1	0	23.00	22.81	23.11	23.08	22.75		0
	1	36	23.02	23.04	23.36	23.21	23.09	0	0
	1	74	22.91	22.76	23.12	22.87	22.99		0
QPSK	36	0	22.07	21.95	22.28	22.19	22.04		1
	36	18	22.14	22.12	22.42	22.24	22.25	0-1	1
	36	37	22.06	22.02	22.46	22.20	22.19	0-1	1
	75	0	22.03	21.99	22.31	22.11	22.12		1
	1	0	22.23	22.10	22.42	22.08	21.76		1
	1	36	22.25	22.31	22.65	22.22	22.06	0-1	1
	1	74	22.20	21.98	22.58	21.81	21.95		1
16QAM	36	0	21.09	21.01	21.26	21.27	21.12		2
	36	18	21.18	21.14	21.37	21.30	21.31	0-2	2
	36	37	21.13	21.05	21.40	21.26	21.27	0-2	2
	75	0	21.09	21.03	21.27	21.18	21.22		2
	1	0	20.85	20.70	21.12	20.88	20.56		2
	1	36	20.95	20.99	21.49	21.02	20.93	0-2	2
	1	74	20.87	20.68	21.29	20.71	20.87		2
64QAM	36	0	20.06	19.98	20.26	20.27	20.14	_	3
	36	18	20.16	20.12	20.35	20.31	20.31	0-3	3
	36	37	20.10	19.99	20.36	20.26	20.31		3
	75	0	20.08	20.04	20.35	20.18	20.19		3

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Table 8-6 LTE Band 41 (2593.0MHz) Conducted Powers – 10MHz Bandwidth

				1	LTE Band 41 0 MHz Bandwidth				
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
		Conducted Power [dBm]							
	1	0	23.10	22.76	23.16	23.08	22.81		0
	1	25	23.09	22.97	23.45	23.26	23.05	0	0
	1	49	23.05	22.77	23.15	23.29	22.81		0
QPSK	25	0	22.11	22.04	22.39	22.22	22.08		1
	25	12	22.16	22.17	22.50	22.32	22.24	0-1	1
	25	25	22.12	22.07	22.48	22.23	22.12	0-1	1
	50	0	22.07	22.12	22.41	22.25	22.19		1
	1	0	22.33	22.09	22.45	21.91	22.15		1
	1	25	22.32	22.31	22.70	22.09	22.38	0-1	1
	1	49	22.34	22.06	22.46	21.85	22.19		1
16QAM	25	0	21.11	20.99	21.43	21.31	21.05		2
	25	12	21.19	21.14	21.49	21.40	21.19	0-2	2
	25	25	21.14	21.03	21.47	21.32	21.09	0-2	2
	50	0	21.11	21.08	21.43	21.28	21.11		2
	1	0	20.96	20.90	21.06	21.23	20.95		2
	1	25	20.96	21.15	21.32	21.42	21.23	0-2	2
	1	49	20.98	20.86	21.03	21.18	20.99		2
64QAM	25	0	20.14	20.02	20.48	20.30	20.07		3
	25	12	20.28	20.15	20.57	20.40	20.22	0-3	3
	25	25	20.19	20.07	20.53	20.35	20.10	0-3	3
	50	0	20.12	20.18	20.48	20.30	20.18	1	3

Table 8-7 LTE Band 41 (2593.0MHz) Conducted Powers - 5MHz Bandwidth

				•	LTE Band 41 MHz Bandwidth	OWEIS - SI			
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	nducted Power [dE	ßm]			
	1	0	23.00	23.03	23.28	23.23	23.17		0
	1	12	23.08	23.02	23.42	23.24	23.14	0	0
	1	24	23.03	23.06	23.34	23.26	23.18		0
QPSK	12	0	22.10	22.12	22.49	22.31	22.15		1
	12	6	22.13	22.19	22.48	22.32	22.24	0-1	1
	12	13	22.15	22.15	22.53	22.37	22.22	0-1	1
	25	0	22.14	22.16	22.50	22.28	22.24	1	1
	1	0	21.88	21.87	22.22	22.08	22.11		1
	1	12	21.90	21.90	22.26	22.06	22.30	0-1	1
	1	24	22.00	21.91	22.29	22.07	22.16	1	1
16QAM	12	0	21.17	21.16	21.57	21.39	21.27		2
	12	6	21.26	21.27	21.59	21.40	21.34	0-2	2
	12	13	21.20	21.23	21.60	21.42	21.30	0-2	2
	25	0	21.18	21.18	21.53	21.31	21.22		2
	1	0	21.16	21.22	21.46	21.38	21.59		2
	1	12	21.20	21.11	21.56	21.40	21.67	0-2	2
	1	24	21.24	21.25	21.57	21.40	21.59		2
64QAM	12	0	20.09	20.23	20.47	20.40	20.24		3
	12	6	20.16	20.31	20.50	20.44	20.27	0-3	3
	12	13	20.13	20.26	20.50	20.43	20.29	] "" [	3
	25	0	20.13	20.20	20.45	20.30	20.18		3

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## b. LTE Band 41 - Power Class 2

Table 8-8
LTE Band 41 (2593.0MHz) Conducted Powers – 20MHz Bandwidth

			(200	······································	LTE Band 41	OWE13 - 20			
				2	0 MHz Bandwidth	,			
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	nducted Power [dE	im]			
	1	0	25.87	26.03	25.99	26.07	25.72		0
	1	50	25.82	25.94	26.34	26.17	25.74	0	0
	1	99	25.88	26.08	26.07	26.23	25.93	] [	0
QPSK	50	0	24.88	25.16	25.33	25.23	24.99		1
	50	25	25.09	25.20	25.44	25.21	24.88	0-1	1
	50	50	25.03	25.19	25.54	25.20	25.20		1
	100	0	24.90	25.10	25.39	25.19	25.13		1
	1	0	25.22	25.51	25.33	25.47	25.13		1
	1	50	25.18	25.49	25.78	25.39	25.61	0-1	1
	1	99	25.30	25.45	25.52	25.13	25.15		1
16QAM	50	0	23.94	24.22	24.34	24.42	24.19		2
	50	25	24.00	24.28	24.43	24.50	24.37	0-2	2
	50	50	23.97	24.22	24.43	24.27	24.43	0-2	2
	100	0	23.95	24.21	24.36	24.38	24.32		2
	1	0	23.94	24.23	23.94	24.15	23.85		2
	1	50	23.93	24.21	24.44	23.98	24.17	0-2	2
	1	99	24.07	24.21	24.16	23.76	24.00	]	2
64QAM	50	0	22.96	23.26	23.36	22.78	23.15	0.0	3
İ	50	25	23.02	23.33	23.48	22.70	23.32		3
ļ	50	50	23.00	23.25	23.44	22.60	23.08	0-3	3
	100	0	22.93	23.20	23.34	22.60	22.97	1	3

Table 8-9
LTE Band 41 (2593.0MHz) Conducted Powers – 15MHz Bandwidth

				<u> </u>	LTE Band 41	OWE13 - 13			
				1	5 MHz Bandwidth				
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	nducted Power [dE	Bm]			
	1	0	26.08	25.77	26.17	26.06	25.94		0
	1	36	26.10	26.00	26.48	26.22	26.20	0	0
	1	74	25.99	25.73	26.24	25.91	26.16		0
QPSK	36	0	25.01	24.94	25.28	25.26	25.03		1
	36	18	25.08	25.11	25.38	25.26	25.23	0-1	1
	36	37	25.05	25.01	25.41	25.24	25.23	0-1	1
	75	0	25.00	24.97	25.26	25.15	25.12		1
	1	0	25.24	25.44	25.37	25.63	25.09	0-1	1
	1	36	25.26	25.66	25.64	25.80	25.41		11
	1	74	25.19	25.38	25.44	25.49	25.38		1
16QAM	36	0	24.10	23.99	24.38	24.21	24.12		2
	36	18	24.20	24.10	24.46	24.22	24.33	0-2	2
	36	37	24.14	24.01	24.54	24.18	24.32	0-2	2
	75	0	24.03	23.99	24.34	24.14	24.17		2
	1	0	24.22	23.95	24.33	24.45	24.09		2
	1	36	24.28	24.18	24.71	24.29	24.45	0-2	2
	1	74	24.20	23.88	24.48	24.07	24.39		2
64QAM	36	0	23.06	22.98	23.36	23.07	23.08	]	3
	36	18	23.17	23.10	23.48	23.03	23.30	0-3	3
	36	37	23.10	22.99	23.48	22.89	23.26	] "-3"	3
	75	0	23.04	23.00	23.33	23.05	23.20		3

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**Table 8-10** LTE Band 41 (2593.0MHz) Conducted Powers – 10MHz Bandwidth

				1	LTE Band 41 0 MHz Bandwidth				
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	nducted Power [dE	Bm]			
	1	0	26.04	25.82	26.17	26.03	25.96		0
	1	25	26.00	26.08	26.46	26.29	26.14	0	0
	1	49	26.05	25.84	26.27	26.07	25.88		0
QPSK	25	0	25.01	25.00	25.37	25.24	25.05		1
	25	12	25.11	25.18	25.49	25.32	25.25	0-1	1
	25	25	25.08	25.05	25.44	25.26	25.14	0-1	1
	50	0	25.04	25.11	25.38	25.20	25.20	1	1
	1	0	25.44	25.45	25.61	25.54	25.30		1
	1	25	25.42	25.72	25.85	25.76	25.55	0-1	1
	1	49	25.33	25.49	25.52	25.55	25.27		1
16QAM	25	0	24.10	24.05	24.40	24.24	24.17		2
	25	12	24.17	24.16	24.56	24.28	24.32	0-2	2
	25	25	24.15	24.10	24.51	24.23	24.20	0-2	2
	50	0	24.07	24.14	24.45	24.20	24.19		2
	1	0	24.41	23.93	24.40	24.33	24.20		2
	1	25	24.40	24.21	24.88	24.20	24.61	0-2	2
	1	49	24.45	23.93	24.60	24.07	24.36		2
64QAM	25	0	23.08	23.12	23.44	23.03	23.15		3
	25	12	23.18	23.26	23.52	23.05	23.31	0-3	3
	25	25	23.13	23.18	23.49	22.92	23.20	U-3	3
	50	0	23.05	23.14	23.40	22.99	23.19	1	3

**Table 8-11** LTE Band 41 (2593.0MHz) Conducted Powers - 5MHz Bandwidth

			`	•	LTE Band 41 MHz Bandwidth	OWEIS - SI			
		RB Size RB Offset	Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size		39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	nducted Power [dE	m]			
	1	0	25.95	26.01	26.29	26.13	26.04		0
	1	12	26.01	26.06	26.41	26.16	26.05	0	0
	1	24	26.02	26.05	26.37	26.17	26.08		0
QPSK	12	0	25.11	25.11	25.53	25.30	25.19		1
	12	6	25.17	25.17	25.52	25.30	25.25	0-1	1
	12	13	25.15	25.16	25.55	25.32	25.23	0-1	1
	25	0	25.11	25.18	25.50	25.31	25.25	1	1
	1	0	25.39	25.07	25.60	25.40	25.34		1
	1	12	25.50	25.15	25.95	25.39	25.59	0-1	1
	1	24	25.39	25.10	25.70	25.37	25.37		1
16QAM	12	0	24.21	24.19	24.63	24.37	24.31		2
	12	6	24.29	24.27	24.67	24.37	24.39	0-2	2
	12	13	24.28	24.21	24.67	24.40	24.34	0-2	2
	25	0	24.14	24.15	24.49	24.35	24.20		2
	1	0	24.40	24.49	24.31	24.55	24.30		2
	1	12	24.42	24.50	24.38	24.40	24.60	0-2	2
	1	24	24.50	24.44	24.36	24.25	24.51		2
64QAM	12	0	23.17	23.21	23.57	23.12	23.27		3
	12	6	23.21	23.28	23.59	23.12	23.34	0-3	3
	12	13	23.19	23.22	23.59	23.05	23.27	] "" [	3
	25	0	23.06	23.17	23.43	22.99	23.17		3

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# c. LTE TDD Uplink Carrier Aggregation

Table 8-12
LTE TDD Uplink Two Component Carrier Aggregation Conducted Powers

	ETE TEE Opinik Two Component Carrier Aggregation Conducted Towers														
				PCC				SCC							Power
Combination	PCC Band	PCC Bandwidth [MHz]	PCC (UL/DL) Channel	PCC (UL/DL) Frequency [MHz]	Modulation	PCC UL# RB	PCC UL RB Offset	SCC Band	SCC Bandwidth [MHz]		SCC (UL/DL) Frequency [MHz]		SCC UL# RB	SCC UL RB Offset	LTE Tx.Power with UL CA Enabled (dBm)
CA_41C (PC3)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	22.86
CA_41C (PC2)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	25.92

## IX. NR FDD Target Powers

Table 8-13 NR FDD Conducted Power Targets

Mode / Band	d	Modulated Average (dBm)
NR Band n71	Maximum	25.0
INN Dallu II/ I	Nominal	24.0
NR Band n5	Maximum	25.0
INK DAIIU IIS	Nominal	24.0
NR Band n66	Maximum	26.0
INN DAILU 1100	Nominal	25.0
NR Band n2	Maximum	25.0
INIT DATIO 112	Nominal	24.0

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## X. NR TDD Conducted Powers

## a. NR n41

Table 8-14
NR n41 (2593.0) Conducted Powers – 100MHz Bandwidth

		NR Band 100 MHz Bar			
			Channel		
Modulation	RB Size	DD 055-14	518598 (2592.99 MHz)	MPR Allowed per 3GPP	MPR [dB]
Wodulation	KD SIZE	RB Offset	Conducted Power [dBm]	[dB]	լսեյ
	1	1	23.94		0
	1	137	23.98	0	0
DFT-s-OFDM	1	271	23.97		0
$\pi/2$ BPSK	135	0	23.47	0-0.5	0.5
n/2 DI SK	135	69	23.96	0	0
	135	138	23.39	0-0.5	0.5
	270	0	23.14	0-0.5	0.5
	1	1	23.95		0
	1	137	23.87	0	0
DET - OFDM	1	271	23.86		0
DFT-s-OFDM QPSK	135	0	22.93	0-1	1
QFSR	135	69	23.73	0	0
	135	138	22.86	0-1	1
	270	0	22.83	U-1	1
DFT-s-OFDM	1	1	22.87	0-1	1
16QAM	1	1	22.21	0-1.5	1.5

Note: Since NR n41 at 100MHz bandwidth does not support 3 non-overlapping channels, conducted power measurements were made only on the middle channel.

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**Table 8-15** NR n41 (2593.0) Conducted Powers - 90MHz Bandwidth

			NR Band n41 MHz Bandwidth			
				nnel		
Modulation	RB Size	PR Offect	508200 528996 Allowe		MPR Allowed per 3GPP	MPR [dB]
			Conducted	Power [dBm]	[dB]	•
	1	1	23.97	23.91		0
	1	123	23.98	23.90	0-0.5	0
DFT-s-OFDM	1	243	24.00	23.87		0
π/2 BPSK	120	0	23.46	23.34	0-0.5	0.5
M/2 DI SK	120	63	23.74	23.68	0	0
	120	125	23.40	23.47	0.05	0.5
	243	0	23.38	23.32		0.5
	1	1	23.96	23.84		0
	1	123	23.94	23.84	0	0
DET OFFIN	1	243	23.98	23.97	] [	0
DFT-s-OFDM QPSK	120	0	22.93	22.81	0-1	1
QF3N	120	63	23.81	23.75	0	0
	120	125	22.84	22.77	0-1	1
	243	0	22.92	22.72	] 0-1	1
DFT-s-OFDM	1	1	22.99	22.85	0-1	1
16QAM	1	1	22.33	22.06	0-1.5	1.5

**Table 8-16** NR n41 (2593.0) Conducted Powers – 90MHz Bandwidth (DFT-s-OFDM 64QAM Only)

THE THE (2000.0) CONTRACTOR OF										
			NR Band r 90 MHz Band							
	Channel									
Modulation	RB Size	RB Offset	508200 (2541 MHz)	518598 (2592.99 MHz)	528996 (2644.98 MHz)	MPR Allowed per 3GPP	MPR [dB]			
			Cond	[dB]						
DFT-s-OFDM 64QAM	1	1	21.29	21.35	21.47	0-2.5	2.5			

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**Table 8-17** NR n41 (2593.0) Conducted Powers - 80MHz Bandwidth

NR Band n41								
		80	MHz Bandwidth		1			
			Cha	nnel				
Modulation	RB Size	RB Offset	507204 (2536.02 MHz)	529998 (2649.99 MHz)	MPR Allowed per 3GPP	MPR [dB]		
			Conducted	Power [dBm]	[dB]			
	1	1	23.68	23.60		0		
	1	109	23.63	23.92	0	0		
DFT-s-OFDM	1	215	23.92	23.95	] [	0		
π/2 BPSK	108	0	23.08	23.13	0-0.5	0.5		
M/2 DI SIC	108	55	23.37	23.61	0	0		
	108	109	22.97	23.23	0-0.5	0.5		
	216	0	23.03	23.11	0-0.5	0.5		
	1	1	23.73	23.55		0		
	1	109	23.65	23.94	0	0		
DFT-s-OFDM	1	215	23.67	23.86		0		
QPSK	108	0	22.64	22.63	0-1	1		
Qi Sit	108	55	23.51	23.56	0	0		
	108	109	22.46	22.62	0-1	1		
	216	0	22.60	22.47	U-1	1		
DFT-s-OFDM 16QAM	1	1	22.92	22.87	0-1	1		
CP-OFDM QPSK	1	1	22.33	21.78	0-1.5	1.5		

**Table 8-18** NR n41 (2593 0) Conducted Powers - 60MHz Bandwidth

NR n41 (2593.0) Conducted Powers – 60MHz Bandwidth  NR Band n41									
			60 MHz Bar						
			OO WII IZ DUI	Channel			MPR [dB]		
Modulation	RB Size	RB Offset	505200 (2526 MHz)	518598 (2592.99 MHz)	531996 (2659.98 MHz)	MPR Allowed per 3GPP			
			Co	[dB]	[uD]				
	1	1	23.62	23.37	23.52		0		
	1	81	23.46	23.36	23.64	0	0		
DFT-s-OFDM	1	160	23.71	23.53	23.80		0		
π/2 BPSK	81	0	23.00	22.95	23.06	0-0.5	0.5		
WZ BF SK	81	41	23.56	23.41	23.67	0	0		
	81	81	23.05	23.01	23.17	0-0.5	0.5		
	162	0	23.17	22.96	23.17	0-0.5	0.5		
	1	1	23.79	23.62	23.73		0		
	1	81	23.94	23.84	23.97	0	0		
DFT-s-OFDM	1	160	23.98	23.99	23.95	Ţ [	0		
QPSK	81	0	22.63	22.40	22.62	0-1	1		
QFSK	81	41	23.39	23.24	23.50	0	0		
	81	81	22.56	22.50	22.71	0-1	1		
-	162	0	22.62	22.45	22.64	U-1	1		
DFT-s-OFDM 16QAM	1	1	22.96	22.86	22.98	0-1	1		
CP-OFDM QPSK	1	1	22.45	22.11	22.22	0-1.5	1.5		

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**Table 8-19** NR n41 (2593 0) Conducted Powers - 50MHz Randwidth

	NR n41 (2593.0) Conducted Powers – 50MHz Bandwidth									
			NR Band 50 MHz Ban							
			50 MINZ Ban	Channel						
Modulation	RB Size	RB Offset	504204 (2521.02 MHz)	518598 (2592.99 MHz)	532998 (2664.99 MHz)	MPR Allowed per 3GPP	MPR [dB]			
			Cor	Bm]	[dB]					
	1	1	23.72	23.62	23.93		0			
	1	67	23.80	23.79	23.87	0	0			
DET - OFDM	1	131	23.99	23.89	23.86		0			
DFT-s-OFDM π/2 BPSK	64	0	23.29	23.16	23.22	0-0.5	0.5			
1.72 DI 31X	64	35	23.72	23.63	23.71	0	0			
	64	69	23.21	23.14	23.24	0-0.5	0.5			
	128	0	23.25	23.31	23.23	0-0.3	0.5			
	1	1	23.95	23.88	23.92		0			
	1	67	23.96	23.72	23.91	0	0			
DET - OFDM	1	131	23.99	23.98	24.00	1	0			
DFT-s-OFDM QPSK	64	0	22.63	22.58	22.84	0-1	1			
QFSK	64	35	23.51	23.41	23.59	0	0			
	64	69	22.89	22.56	22.70	0-1	1			
	128	0	22.68	22.57	22.65	U-1	1			
DFT-s-OFDM 16QAM	1	1	22.96	22.87	22.91	0-1	1			
CP-OFDM QPSK	1	1	22.50	22.30	22.33	0-1.5	1.5			

**Table 8-20** NR n41 (1882.5MHz) Conducted Powers - 40MHz Bandwidth

NR Band n41 40 MHz Bandwidth										
				Cha	nnel					
Modulation	RB Size	Size RB Offset	503202 (2516.01 MHz)	513468 (2567.34 MHz)	523734 (2618.67 MHz)	534000 (2670 MHz)	MPR Allowed per 3GPP	MPR Allowed per 3GPP		
			Conducted Power [dBm]				[dB]	[dB]		
	1	1	23.85	23.95	23.83	23.87		0		
	1	53	23.92	24.00	23.91	23.98	0	0		
DFT-s-OFDM	1	104	23.97	23.97	23.93	23.98		0		
π/2 BPSK	50	0	23.43	23.46	23.40	23.50	0-0.5	0.5		
WZ DI SIC	50	28	23.98	23.94	23.95	23.96	0	0		
	50	56	23.50	23.50	23.50	23.46	0-0.5	0.5		
	100	0	23.46	23.41	23.42	23.48		0.5		
	1	1	23.85	23.84	23.93	23.95		0		
	1	53	23.94	23.87	23.92	23.85	0	0		
DFT-s-OFDM	1	104	23.92	23.76	23.98	23.89		0		
OPSK	50	0	23.00	22.97	22.73	22.99	0-1	1		
QI OIL	50	28	23.79	23.80	23.79	23.84	0	0		
	50	56	22.90	22.94	23.00	22.99	0-1	1		
	100	0	22.88	22.99	22.90	22.96	0-1	1		
DFT-s-OFDM 16QAM	1	1	22.97	22.96	22.93	23.00	0-1	1		
CP-OFDM QPSK	1	1	22.49	22.41	22.25	22.45	0-1.5	1.5		

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## **Table 8-21** NR n41 (1882 5MHz) Conducted Powers - 20MHz Bandwidth

NR n41 (1882.5MHz) Conducted Powers – 20MHz Bandwidth									
				NR Band					
				20 MHz Ban	Channel				
Modulation RB	RB Size	RB Offset	501204 (2506.02 MHz)	509898 (2549.49 MHz)	518598 (2592.99 MHz)	527298 (2636.49 MHz)	535998 (2679.99 MHz)	MPR Allowed per 3GPP	MPR [dB]
			Conducted Power [dBm]						,
	1	1	23.89	23.87	23.83	23.88	23.85		0
	1	26	23.91	23.86	23.86	23.85	23.92	0	0
DFT-s-OFDM π/2 BPSK	1	49	23.99	23.70	23.79	24.00	23.93		0
	25	0	23.43	23.30	23.15	23.38	23.50	0-0.5	0.5
WZ DI SK	25	13	23.88	23.74	23.52	23.80	23.96	0	0
	25	26	23.41	23.36	23.26	23.42	23.28	0-0.5	0.5
	50	0	23.46	23.29	23.21	23.39	23.46		0.5
	1	1	23.87	23.92	23.79	23.91	23.83		0
	1	26	23.98	23.96	23.95	23.82	23.95	0	0
DFT-s-OFDM	1	49	23.93	23.81	23.98	23.88	23.86	] [	0
QPSK	25	0	22.95	22.99	22.72	22.99	22.93	0-1	1
Qi Sit	25	13	23.81	23.76	23.61	24.00	23.78	0	0
	25	26	22.80	22.81	22.83	22.96	22.85	0-1	1
	50	0	22.86	22.89	22.69	22.97	22.85	U-1	1
DFT-s-OFDM 16QAM	1	1	22.96	22.84	22.77	22.70	22.85	0-1	1
CP-OFDM QPSK	1	1	22.50	22.31	22.35	22.28	22.33	0-1.5	1.5

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# XI. WIFI Target Powers (SISO)

Table 8-22 2.4GHz IEEE 802.11b/g/n Reduced Average RF Power Targets<sup>1</sup>

ELE COZ: 115/g/11 Reduced Average Ri 1 ower								
	Band	IEEE 802.11 (in dBm)						
Mode		SISO						
		Antenna 1						
		b	g	n				
2.4 GHz WIFI	2.45 GHz	13.0	13.0	13.0				

(Upper tolerance: target +1.0dB)

Table 8-23
5GHz IEEE 802.11a/n/ac Reduced Average RF Power Targets<sup>1</sup>

_ <u>LL 002.</u>	i ia/ii/ac	Reduced A	Average in	I LOME!
		IEE	E 802.11 (in di	3m)
Mode	Band		SISO	
Wode	Band		Antenna 1	
		а	n	ac
	5200 MHz	10.0	10.0	10.0
5 GHz WIFI	5300 MHz	10.0	10.0	10.0
(20MHz BW)	5500 MHz	10.0	10.0	10.0
	5800 MHz	10.0	10.0	10.0
	5200 MHz		10.0	10.0
5 GHz WIFI	5300 MHz		10.0	10.0
(40MHz BW)	5500 MHz		10.0	10.0
	5800 MHz		10.0	10.0
	5200 MHz			10.0
5 GHz WIFI	5300 MHz			10.0
(80MHz BW)	5500 MHz			10.0
	5800 MHz			10.0

(Upper tolerance: target +1.0dB)

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<sup>&</sup>lt;sup>1</sup> Note: This device utilizes independent power reduction mechanisms for the WIFI transmitter in all WIFI modes for held-to-ear scenarios.

# 9. JUSTIFICATION OF HELD TO EAR MODES TESTED

# I. Analysis of RF Air Interface Technologies

An analysis was performed, following the guidance of §4.3 and §4.4 of the ANSI standard, of the RF air interface technologies being evaluated. The factors that will affect the RF interference potential were evaluated, and the worst-case operating modes were identified and used in the evaluation. A WD's interference potential is a function both of the WD's average near-field field strength and of the signal's audio-frequency amplitude modulation characteristics. Per §4.4, RF air interface technologies that have low power have been found to produce sufficiently low RF interference potential, so it is possible to exempt them from the product testing specified in Clause 5 of the ANSI standard. An RF air interface technology of a device is exempt from testing when its average antenna input power plus its MIF is ≤17dBm for all of its operating modes. RF air interface technologies exempted from testing in this manner are automatically assigned an M4 rating to be used in determining the overall rating for the WD.

The worst-case MIF plus the worst-case average antenna input power for all modes are investigated below to determine the testing requirements for this device.

### II. Individual Mode Evaluations

Table 9-1

Max Power + MIF calculations for Low Power Exemptions

Air Interface	Maximum Average Power (dBm)	Worst Case MIF (dB)	Total (Power + MIF, dB)	C63.19 Testing Required
CDMA - Full Frame Rate (RC1/SO55)	24.73	-19.68	5.05	No
CDMA - 1/8 <sup>th</sup> Frame Rate (RC1/SO3)	15.70*	3.05	18.75	Yes
CDMA - EvDO	25.90	-19.35	6.55	No
GSM - GSM850	23.50*	3.54	27.04	Yes
GSM - GSM1900	20.85*	3.54	24.39	Yes
GSM - EDGE850	17.93*	3.76	21.69	Yes <sup>1</sup>
GSM - EDGE1900	17.03*	3.73	20.76	Yes <sup>1</sup>
UMTS - RMC	25.00	-21.08	3.92	No
UMTS - AMR	25.00	-22.27	2.73	No
UMTS - HSPA	24.00	-22.04	1.96	No
LTE FDD	25.50	-9.69	15.81	No
LTE TDD - Band 41 (PC3)	16.76*	1.52	18.28	Yes
LTE TDD - Band 41 (PC2)	19.79*	1.57	21.36	Yes
LTE TDD - Uplink Carrier Aggregation	19.23*	1.47	20.70	Yes <sup>2</sup>
NR FDD	26.00	-9.38	16.62	No
NR TDD	17.98*	1.56	19.54	Yes
WIFI - 2.4GHz	14.00	-8.33	5.67	No
WIFI - 5GHz	11.00	-8.83	2.17	No

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\*Note: ANSI C63.19-2011 Sec. 4.4 Footnote 20 indicates the use of a long averaging time for measuring the antenna input power when using this method of exclusion. Therefore, the frame averaged power was calculated for these modes in this investigation.

## **III. Low-Power Exemption Conclusions**

Per ANSI C63.19-2011, RF Emissions testing for this device is required only for GSM and CDMA 1/8<sup>th</sup> Frame Rate voice modes as well as LTE TDD (Power Class 3 and Power Class 2) and NR TDD data modes. All other air interfaces are exempt.

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<sup>&</sup>lt;sup>1</sup> Note: EDGE data modes were considered but not tested as GSM voice modes were found to be the worst-case modes for the GSM air interface.

<sup>&</sup>lt;sup>2</sup> Note: LTE TDD Uplink Carrier Aggregation was considered but not tested as LTE TDD standalone data modes were found to be the worst-case modes for the LTE TDD air interface.

## 10. LTE TDD UPLINK-DOWNLINK CONFIGURATION

## I. Uplink-Downlink Configuration Additional Testing

Additional testing was performed on each supported power class for LTE TDD to determine the worst-case Uplink-Downlink configuration for RFE testing.

Per 3GPP TS 36.211, the total frame length for each TDD radio frame of length  $T_f$  = 307200 ·  $T_s$  = 10 ms, where  $T_s$  is a number of time units equal to 1/(15000 x 2048) seconds. Additionally, each radio frame consists of 10 subframes, each of length 30720 ·  $T_s$  = 1 ms, and subframes can be designated as uplink (U), downlink (D), or special subframe (S), depending on the Uplink-Downlink configuration as indicated in Table 4.2-2 of 3GPP TS 36.211. In the transmission duty factor calculation, the special subframe configuration with the shortest UpPTS duration within the special subframe is used and will be applied for measurement. From 3GPP TS 36.211 Table 4.2-1, the shortest UpPTS is 2192 · Ts which occurs in the normal cyclic prefix and special subframe configuration 4.

See table below outlining the calculated transmission duty cycles for each Uplink-Downlink configuration:

**Table 10-1**Uplink-Downlink Configurations for Type 2 Frame Structures

Uplink-downlink configuration	Downlink-to-Uplink Switch-point periodicity		Subframe number									Calculated Transmission
configuration	Switch-point periodicity	0	1	2	3	4	5	6	7	8	9	Duty Cycle (%)
0	5 ms	D	S	U	U	U	D	S	U	U	U	61.4%
1	5 ms	D	S	U	U	D	D	S	U	U	D	41.4%
2	5 ms	D	S	U	D	D	D	S	U	D	D	21.4%
3	10 ms	D	S	U	U	U	D	D	D	D	D	30.7%
4	10 ms	D	S	U	U	D	D	D	D	D	D	20.7%
5	10 ms	D	S	U	D	D	D	D	D	D	D	10.7%
6	5 ms	D	S	U	U	U	D	S	U	U	D	51.4%

# II. Power Class 3 Uplink-Downlink Configuration Additional Testing

LTE TDD was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 3, all configurations (0-6) are supported. The configuration which resulted in the worst-case emission was used for full testing. See Table 10-2 below for results. The configuration determined in the results below was used to measure the MIF values in Table 7-5 & Table 7-7.

**Table 10-2**LTE TDD Power Class 3 UL-DL Configuration Results

	ETE TOD TOWER Glass & GE-DE Confliguration results														
Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	ons														
	20	40620	0	16QAM	1	0	Acoustic	10.93	20.77	-3.34	17.43	35.00	-17.57	M4	1,2,4
	20	40620	1	16QAM	1	0	Acoustic	9.23	19.30	-1.58	17.72	35.00	-17.28	M4	1,2,4
	20	40620	2	16QAM	1	0	Acoustic	7.10	17.03	1.46	18.49	35.00	-16.51	M4	1,4,7
LTE TDD / Band 41	20	40620	3	16QAM	1	0	Acoustic	8.26	18.34	-1.50	16.84	35.00	-18.16	M4	1,4,7
	20	40620	4	16QAM	1	0	Acoustic	6.94	16.82	0.66	17.48	35.00	-17.52	M4	1,2,4
	20	40620	5	16QAM	1	0	Acoustic	5.38	14.62	3.62	18.24	35.00	-16.76	M4	1,2,4
	20	40620	6	16QAM	1	0	Acoustic	9.92	19.93	-2.54	17.39	35.00	-17.61	M4	1,2,4

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# III. Power Class 2 Uplink-Downlink Configuration Additional Testing

LTE TDD was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 2, only configurations 1-5 are supported. The configuration which resulted in the worst-case emission was used for full testing. See Table 10-3 below for results. The configuration determined in the results below was used to measure the MIF values in Table 7-6 & Table 7-7.

**Table 10-3**LTE TDD Power Class 2 UL-DL Configuration Results

Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	ons														
	20	40620	1	16QAM	1	0	Acoustic	13.26	22.45	-1.57	20.88	35.00	-14.12	M4	1,2,3
	20	40620	2	16QAM	1	0	Acoustic	9.65	19.69	1.43	21.12	35.00	-13.88	M4	1,2,3
LTE TDD / Band 41	20	40620	3	16QAM	1	0	Acoustic	11.33	21.08	-1.47	19.61	35.00	-15.39	M4	1,2,3
	20	40620	4	16QAM	1	0	Acoustic	9.11	19.19	0.59	19.78	35.00	-15.22	M4	1,2,3
	20	40620	5	16QAM	1	0	Acoustic	7.01	16.91	3.78	20.69	35.00	-14.31	M4	1,2,4

## **IV. Conclusion**

Per the results above, UL-DL Configuration 2 was used for both LTE TDD Power Class 3 and Power Class 2 testing.

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# 11. OVERALL MEASUREMENT SUMMARY

FCC ID:	A3LSMA716U
S/N:	06243

## I. E-FIELD EMISSIONS:

# Table 11-1 HAC Data Summary for E-field – CDMA

			-		•	ilai y ioi		ODIVIA	-			
Mode	Channel	RC/SO	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	ons											
	564*	RC1/SO3	Acoustic	24.73	10.98	20.81	3.04	23.85	45.00	-21.15	M4	7,8,9
Cellular CDMA	1013	RC1/SO3	Acoustic	24.71	11.04	20.86	3.01	23.87	45.00	-21.13	M4	7,8,9
Celiulai CDIVIA	384	RC1/SO3	Acoustic	24.64	9.61	19.65	3.05	22.70	45.00	-22.30	M4	6,8,9
	777	RC1/SO3	Acoustic	24.69	9.67	19.71	3.01	22.72	45.00	-22.28	M4	4,7,8
	25	RC1/SO3	Acoustic	24.37	6.82	16.68	3.01	19.69	35.00	-15.31	M4	1,2,3
PCS CDMA	600	RC1/SO3	Acoustic	24.18	6.68	16.49	3.02	19.51	35.00	-15.49	M4	1,2,3
	1175	RC1/SO3	Acoustic	24.08	6.03	15.61	3.05	18.66	35.00	-16.34	M4	1,2,3

<sup>\*</sup>Note: Cell. CDMA Ch. 564 is the Part 90S test channel.

Table 11-2
HAC Data Summary for E-field – GSM

	TIAO Data Sulfilliary for L-field - Com											
Mode	Channel	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5	
E-Field Emission	ons											
	128	Acoustic	32.69	26.77	28.55	3.54	32.09	45.00	-12.91	M4	6,8,9	
GSM850	190	Acoustic	32.55	28.07	28.96	3.54	32.50	45.00	-12.50	M4	6,8,9	
	251	Acoustic	32.59	28.23	29.01	3.54	32.55	45.00	-12.45	M4	6,8,9	
	512	Acoustic	30.04	8.69	18.78	3.53	22.31	35.00	-12.69	M4	1,2,3	
GSM1900	661	Acoustic	29.38	8.88	18.97	3.54	22.51	35.00	-12.49	M4	1,2,3	
	810	Acoustic	29.92	8.97	19.06	3.53	22.59	35.00	-12.41	M4	1,2,3	

# Table 11-3 HAC Data Summary for E-field – LTE B41 (PC3)

Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
	10	39750	2	16QAM	1	0	Acoustic	22.33	6.41	16.14	1.51	17.65	35.00	-17.35	M4	1,2,3
	10	40185	2	16QAM	1	0	Acoustic	22.09	6.62	16.41	1.41	17.82	35.00	-17.18	M4	1,2,3
LTE TDD / Band 41 PC3	10	40620	2	16QAM	1	0	Acoustic	22.45	6.38	16.09	1.52	17.61	35.00	-17.39	M4	1,2,4
Build 411 00	10	41055	2	16QAM	1	0	Acoustic	21.91	7.26	17.22	1.39	18.61	35.00	-16.39	M4	7,8,9
	10	41490	2	16QAM	1	0	Acoustic	22.15	6.54	16.31	1.50	17.81	35.00	-17.19	M4	1,2,3

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**Table 11-4** HAC Data Summary for E-field – LTE B41 (PC2)

	TIAO Data Gaillinary for E ficial ETE D41 (1 GE)															
Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.		RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	ons															
	15	39750	2	16QAM	1	36	Acoustic	25.26	7.14	17.07	1.56	18.63	35.00	-16.37	M4	1,2,3
	15	40185	2	16QAM	1	36	Acoustic	25.66	9.10	19.18	1.47	20.65	35.00	-14.35	M4	1,2,3
LTE TDD / Band 41 PC2	15	40620	2	16QAM	1	36	Acoustic	25.64	8.81	18.90	1.57	20.47	35.00	-14.53	M4	1,2,3
	15	41055	2	16QAM	1	36	Acoustic	25.80	9.24	19.31	1.43	20.74	35.00	-14.26	M4	1,2,3
	15	41490	2	16QAM	1	36	Acoustic	25.41	8.68	18.77	1.57	20.34	35.00	-14.66	M4	1,2,3

**Table 11-5** HAC Data Summary for E-field - NR n41

					.,	_ ~ ~ .		∝.,								
Mode / Band	Bandwidth (MHz)	Channel	Waveform	Mod.	RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emission	ons															
	90	508200	DFT-s-OFDM	64QAM	1	1	Acoustic	21.29	15.23	23.65	1.53	25.18	35.00	-9.82	M4	2,3,6
NR TDD / n41	90	518598	DFT-s-OFDM	64QAM	1	1	Acoustic	21.35	17.91	25.06	1.56	26.62	35.00	-8.38	M4	2,3,6
NK IDD / N41	90	528996	DFT-s-OFDM	64QAM	1	1	Acoustic	21.47	18.08	25.14	1.52	26.66	35.00	-8.34	M4	2,3,6
	90	528996	DFT-s-OFDM	64QAM	1	1	T-Coil	21.47	15.98	24.07	1.52	25.59	35.00	-9.41	M4	2,3,6



Figure 11-1 Sample E-field Scan Overlay (See Test Setup Photographs for actual WD overlay)

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# II. Worst-case Configuration Evaluation

Table 11-6
Peak Reading 360° Probe Rotation at Azimuth axis

Mode	Bandwidth (MHz)	Channel	UL-DL Config.	Mod.	RB Size	200		Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
Probe Rotation	Probe Rotation at Worst-Case														
NR TDD / n41	90	528996	DFT-s-OFDM	64QAM	1	1	Acoustic	19.51	25.81	1.52	27.33	35.00	-7.67	M4	2,3,6

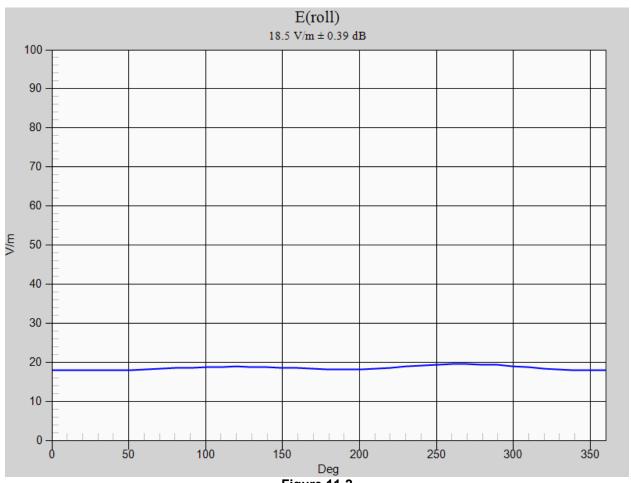


Figure 11-2
Worst-Case Probe Rotation about Azimuth axis

\* Note: Locations of probe rotation (with and without exclusions) are shown in Figure 11-1 denoted by the green square markers.

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# 12. EQUIPMENT LIST

# **Table 12-1** Equipment List

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	E4438C	ESG Vector Signal Generator	5/23/2019	Annual	5/23/2020	MY47270002
Agilent	N5182A	MXG Vector Signal Generator	7/10/2019	Annual	7/10/2020	MY47420800
Agilent	N9020A	MXA Signal Analyzer	4/29/2019	Annual	4/29/2020	MY54500644
Amplifier Research	15S1G6	Amplifier	N/A	CBT*	N/A	433978
Anritsu	MA24106A	USB Power Sensor	6/21/2019	Annual	6/21/2020	1244515
Anritsu	MA24106A	USB Power Sensor	7/8/2019	Annual	7/8/2020	1248508
Anritsu	MA2411B	Pulse Power Sensor	12/4/2019	Annual	12/4/2020	1126066
Anritsu	MA2411B	Pulse Power Sensor	8/8/2019	Annual	8/8/2020	1339008
Anritsu	ML2496A	Power Meter	11/6/2019	Annual	11/6/2020	1405003
Control Company	4040	Temperature / Humidity Monitor	10/9/2018	Biennial	10/9/2020	181647812
Mini-Circuits	NLP-1200+	Low Pass Filter DC to 1000 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	NLP-2950+	Low Pass Filter DC to 2700 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	BW-N20W5	Power Attenuator	N/A	CBT*	N/A	1226
Pasternack	PE2237-20	Bidirectional Coupler	N/A	CBT*	N/A	N/A
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	6/6/2019	Annual	6/6/2020	161662
Rohde & Schwarz	CMW500	Radio Communication tester	8/14/2019	Annual	8/14/2020	140144
Seekonk	NC-100	Torque Wrench (8" lb)	5/23/2018	Biennial	5/23/2020	N/A
SPEAG	AIA	Audio Interference Analzyer	N/A	CBT*	N/A	1010
SPEAG	EF3DV3	Freespace E-field Probe	1/16/2019	Biennial	1/16/2021	4035
SPEAG	CD835V3	Freespace 835 MHz Dipole	2/19/2019	Biennial	2/19/2021	1003
SPEAG	CD1880V3	Freespace 1880 MHz Dipole	2/19/2019	Biennial	2/19/2021	1137
SPEAG	CD2600V3	Freespace 2600MHz Dipole	2/19/2019	Biennial	2/19/2021	1012
SPEAG	DAE4	Dasy Data Acquisition Electronics	2/12/2020	Annual	2/12/2021	665

Calibration traceable to the National Institute of Standards and Technology (NIST).

\*Note: CBT (Calibrated Before Testing). Prior to testing, the measurement paths containing a cable, attenuator, coupler or filter were connected to a calibrated source (i.e. a signal generator) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements.

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# 13. MEASUREMENT UNCERTAINTY

# **Table 13-1**Uncertainty Estimation Table

		Jncertainty communication					
		Uncert	ainty Estima	ation			
Uncertainty Component	Data (dB)	Data Type	Prob. Dist.	Divisor	Ci (E)	Unc. (dB)	Notes/Comments
Measurement System	-		-			-	
RF System Reflections	0.50	Tolerance	N	1.00	1	0.50	* Refl. < -20 dB
Field Probe Calibration	0.21	Tolerance	N	1.00	1	0.21	
Field Probe Isotropy	0.01	Tolerance	N	1.00	1	0.01	
Field Probe Frequency Response	0.135	Tolerance	N	1.00	1	0.14	
Field Probe Linearity	0.013	Tolerance	N	1.00	1	0.01	
Modulation Interference Factor	0.20	Tolerance	R	1.73	1	0.12	Applicable for M-rating testing
Boundary Effects	0.105	Accuracy	R	1.73	1	0.06	*
Probe Positioning Accuracy	0.20	Accuracy	R	1.73	1	0.12	*
Probe Positioner	0.050	Accuracy	R	1.73	1	0.03	*
Extrapolation/Interpolation	0.045	Tolerance	R	1.73	1	0.03	*
Resolution to 2mm error	0.21	Tolerance	N	1.00	1	0.21	
System Detection Limit	0.05	Tolerance	R	1.73	1	0.03	*
Readout Electronics	0.015	Tolerance	N	1.00	1	0.02	*
Integration Time	0.11	Tolerance	R	1.73	1	0.06	*
Response Time	0.033	Tolerance	R	1.73	1	0.02	*
Phantom Thickness	0.10	Tolerance	R	1.73	1	0.06	*
System Repeatability (Field x 2=power)	0.17	Tolerance	N	1.00	1	0.17	*
Test Sample Related							
Device Positioning Vertical	0.2	Tolerance	R	1.73	1	0.12	*
Device Positioning Lateral	0.045	Tolerance	R	1.73	1	0.03	*
Device Holder and Phantom	0.1	Tolerance	R	1.73	1	0.06	*
Power Drift	0.21	Tolerance	R	1.73	1	0.12	
Combined Standard Uncertainty (k=1)						0.66	16.3%
Expanded Uncertainty [95% confidence]					1.31	32.6%	
Expanded Uncertainty [95% confidence]	on Field					0.66	16.3%

### Notes:

- Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297. All
  equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81
  and NIST Tech Note 1297 and UKAS M3003.
- 2. \* Uncertainty specifications from Schmidt & Partner Engineering AG (not site specific)

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid immunity tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

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#### TEST DATA 14.

See following Attached Pages for Test Data.

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#### DUT: CD835V3 - SN1003

Type: CD835V3 Serial: 1003

#### Communication System: CW; Frequency: 835 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

## DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

#### 835 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x361x1):

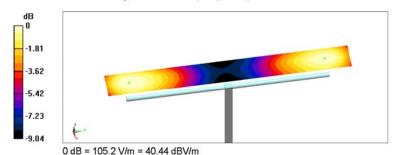
Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 128.9 V/m; Power Drift = -0.15 dB

Applied MIF = 0.00 dB

Average Value of Peak (interpolated) = 104.5 V/m



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#### DUT: CD1880V3 - SN1137

Type: CD1880V3 Serial: 1137

#### Communication System: CW; Frequency: 1880 MHz;

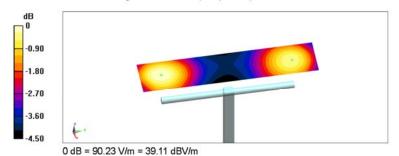
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

## DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

#### 1880 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 146.0 V/m; Power Drift = 0.07 dB
Applied MIF = 0.00 dB
Average Value of Peak (interpolated) = 88.5 V/m



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### DUT: CD2600V3 - SN1012

Type: CD2600V3 Serial: 1012

#### Communication System: CW; Frequency: 2600 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

## DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

#### 2600 MHz / 100mW HAC Dipole Validation at 15mm/Hearing Aid Compatibility Test (41x181x1):

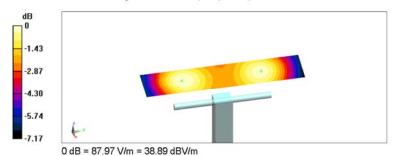
Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 68.76 V/m; Power Drift = -0.01 dB

Applied MIF = 0.00 dB

Average Value of Peak (interpolated) = 87.1 V/m



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Type: Portable Handset Serial: 06243 Backlight off Duty Cycle: 1:8

#### Communication System: CDMA; Frequency: 824.7 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
  Measurement SW: DASY52, Version 52.10 (0);

### Cellular CDMA Low Channel/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 15.00 V/m; Power Drift = 0.16 dB
Applied MIF = 3.01 dB
RE audio interference local = 0.07 dB RF audio interference level = 23.87 dBV/m Emission category: M4

### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
22.91 dBV/m	23.3 dBV/m	22.92 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
23.35 dBV/m	23.87 dBV/m	23.66 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
24.55 dBV/m	24.73 dBV/m	24.04 dBV/m



#### DCTEST 2020

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Date: 4/27/2020



#### DUT: A3LSMA716U

Type: Portable Handset Serial: 06243 Backlight off Duty Cycle: 1:8

#### Communication System: CDMA; Frequency: 1851.25 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

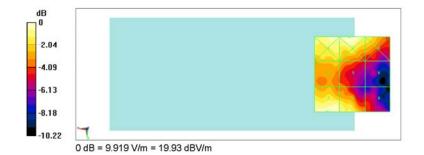
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

## PCS CDMA Low Channel/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 6.068 V/m; Power Drift = -0.12 dB
Applied MIF = 3.01 dB
RF audio interference level = 19.69 dBV/m
Emission category: M4

#### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
19.85 dBV/m	19.93 dBV/m	18.9 dBV/m
1 Section 1 1 representation of the control of the	and the second second second second	Grid 6 M4 14.84 dBV/m
		Grid 9 M4 16.02 dBV/m



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Date: 4/27/2020



### **DUT: A3LSMA716U**

Type: Portable Handset Serial: 06243 Backlight off Duty Cycle: 1:8.3

#### Communication System: GSM; Frequency: 848.8 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

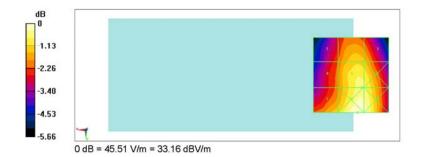
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

## GSM850 High Channel/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 38.66 V/m; Power Drift = -0.15 dB
Applied MIF = 3.54 dB
RF audio interference level = 32.55 dBV/m
Emission category: M4

#### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
30.95 dBV/m	31.95 dBV/m	31.8 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
31.19 dBV/m	32.55 dBV/m	32.51 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
32.08 dBV/m	33.16 dBV/m	33.02 dBV/m



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Type: Portable Handset Serial: 06243 Backlight off Duty Cycle: 1:8.3

#### Communication System: GSM; Frequency: 1909.8 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

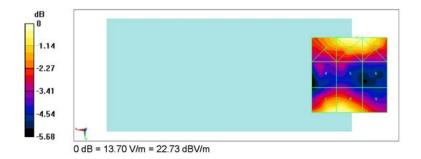
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
  Measurement SW: DASY52, Version 52.10 (0);

### GSM1900 High Channel/Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 7.535 V/m; Power Drift = 0.11 dB
Applied MIF = 3.53 dB RF audio interference level = 22.59 dBV/m Emission category: M4

### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
21.81 dBV/m	22.74 dBV/m	22.69 dBV/m
The state of the s	Grid 5 M4 19.73 dBV/m	Grid 6 M4 19.1 dBV/m
Grid 7 M4 22.59 dBV/m		Grid 9 M4 21.16 dBV/m



#### DCTEST 2020

FC1ES1 2020						
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Type: Portable Handset Serial: 06243 Backlight off Duty Cycle: 1:4.67

#### Communication System: LTE TDD41; Frequency: 2636.5 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

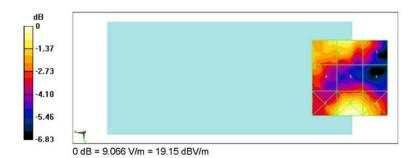
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

# Power Class 3 TDD LTE Band 41 Mid High Channel, UL-DL 2, 10MHz, 16QAM, 1 RB, 0 RB Offset, Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 6.799 V/m; Power Drift = 0.10 dB
Applied MIF = 1.39 dB
RF audio interference level = 18.61 dBV/m
Emission category: M4

#### MIF scaled E-field

Grid 1 <b>M4</b>	Grid 2 M4	Grid 3 M4
18.43 dBV/m	18.61 dBV/m	17.47 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
17.27 dBV/m	16.2 dBV/m	16.14 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
17.92 dBV/m	19.15 dBV/m	18.33 dBV/m



PCTEST 2020							
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Type: Portable Handset Serial: 06243 Backlight off Duty Cycle: 1:4.67

#### Communication System: LTE TDD41; Frequency: 2636.5 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
  Measurement SW: DASY52, Version 52.10 (0);

#### Power Class 2 TDD LTE Band 41 Mid High Channel, UL-DL 2, 15MHz, 16QAM, 1 RB, 36 RB Offset Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 8.919 V/m; Power Drift = -0.10 dB Applied MIF = 1.43 dB RF audio interference level = 20.74 dBV/m Emission category: M4

#### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
20.99 dBV/m	21.42 dBV/m	20.78 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
18.91 dBV/m	18.78 dBV/m	18.5 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
19.67 dBV/m	20.74 dBV/m	20.36 dBV/m



#### DCTEST 2020

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Type: Portable Handset Serial: 06243 Backlight off Duty Cycle: 1:4

#### Communication System: n41; Frequency: 2644.98 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

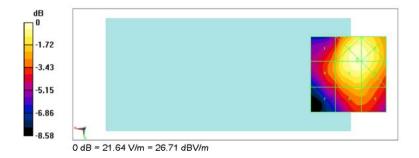
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 2/12/2020
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
  Measurement SW: DASY52, Version 52.10 (0);

#### NR TDD n41 High Channel, 90MHz, DFT-s-OFDM, 64QAM, 1 RB, 1RB Offset, Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 25.03 V/m; Power Drift = -0.06 dB Applied MIF = 1.52 dB RF audio interference level = 26.66 dBV/m Emission category: M4

#### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
24.17 dBV/m	26.7 dBV/m	26.57 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
24.36 dBV/m	26.66 dBV/m	26.54 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
22.78 dBV/m	24.67 dBV/m	24.6 dBV/m



#### DCTEST 2020

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#### CALIBRATION CERTIFICATES 15.

The following pages include the probe calibration used to evaluate HAC for the DUT.

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#### Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
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Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 0108

Cfient

PC Test

Certificate No: EF3-4035 Jan19/2

# CALIBRATION CERTIFICATE (Replacement of No: EF3-4035\_Jan19)

Object

EF3DV3- SN:4035

Calibration procedure(s)

QA CAL-02.v9, QA CAL-25.v7

Calibration procedure for E-field probes optimized for close near field

evaluations in air

Calibration date:

January 16, 2019

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature ( $22 \pm 3$ )°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	04-Apr-18 (No. 217-02672/02673)	Apr-19
Power sensor NRP-Z91	SN: 103244	04-Apr-18 (No. 217-02672)	Apr-19
Power sensor NRP-Z91	SN: 103245	04-Apr-18 (No. 217-02673)	Apr-19
Reference 20 dB Attenuator	SN: S5277 (20x)	04-Apr-18 (No. 217-02682)	Apr-19
DAE4	SN: 789	14-Jan-19 (No. DAE4-789_Jan19)	Jan-20
Reference Probe ER3DV6	SN: 2328	09-Oct-18 (No. ER3-2328_Oct18)	Oct-19
Secondary Standards	ID	Check Date (in house)	Scheduled Check
Power meter E4419B	SN: GB41293874	06-Apr-16 (in house check Jun-18)	In house check: Jun-20
Power sensor E4412A	SN: MY41498087	06-Apr-16 (in house check Jun-18)	In house check: Jun-20
Power sensor E4412A	SN: 000110210	06-Apr-16 (in house check Jun-18)	In house check; Jun-20
RF generator HP 8648C	SN: US3642U01700	04-Aug-99 (in house check Jun-18)	In house check: Jun-20
Network Analyzer E8358A	SN: US41080477	31-Mar-14 (in house check Oct-18)	In house check: Oct-19

	Name	Function	Signature	
Calibrated by:	Manu Seitz	Laboratory Technician		
			et as	•
Approved by:	Katja Pokovic	Technical Manager		
ripprotod by:	raga i oxovic	recitifical Mariager	6166	

Issued: February 11, 2019

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: EF3-4035\_Jan19/2

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#### Calibration Laboratory of

Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





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Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Glossary:

NORMx,y,z sensitivity in free space DCP diode compression point

crest factor (1/duty\_cycle) of the RF signal CF A, B, C, D modulation dependent linearization parameters

En incident E-field orientation normal to probe axis incident E-field orientation parallel to probe axis Ep

Polarization φ φ rotation around probe axis

Polarization 9 9 rotation around an axis that is in the plane normal to probe axis (at measurement center),

i.e., 9 = 0 is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot coordinate system

#### Calibration is Performed According to the Following Standards:

a) IEEE Std 1309-2005, "IEEE Standard for calibration of electromagnetic field sensors and probes, excluding antennas, from 9 kHz to 40 GHz", December 2005
b) CTIA Test Plan for Hearing Aid Compatibility, Rev 3.1.1, May 2017

#### Methods Applied and Interpretation of Parameters:

- NORMx,y,z: Assessed for E-field polarization  $\vartheta=0$  for XY sensors and  $\vartheta=90$  for Z sensor (f  $\leq 900$  MHz in TEM-cell; f > 1800 MHz: R22 waveguide).
- $NORM(f)x,y,z = NORMx,y,z * frequency_response$  (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics
- Ax,y,z; Bx,y,z; Cx,y,z; Dx,y,z; VRx,y,z: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. *VR* is the maximum calibration range expressed in RMS voltage across the diode.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

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# DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

#### **Basic Calibration Parameters**

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm (μV/(V/m) <sup>2</sup> )	0.90	0.74	1.20	± 10.1 %
DCP (mV) <sup>B</sup>	96.8	98.5	95.3	

Calibration results for Frequency Response (30 MHz - 6 GHz)

Frequency MHz	Target E-Field V/m	Measured E-field (En) V/m	Deviation E-normal in %	Measured E-field (Ep) V/m	Deviation E-normal in %	Unc (k=2) %
30	77.3	76.8	-0.6%	77.3	0.1%	± 5.1 %
100	77.3	78.2	1.2%	77.8	0.7%	± 5.1 %
450	77.1	78.2	1.5%	77.8	0.9%	± 5.1 %
600	77.1	77.8	0.9%	77.5	0.5%	± 5.1 %
750	77.3	77.7	0.5%	77.2	-0.1%	± 5.1 %
1800	140.3	136.9	-2.4%	137.2	-2.2%	± 5.1 %
2000	133.0	129.4	-2.8%	129.4	-2.7%	± 5.1 %
2200	124.8	121.5	-2.7%	122.7	-1.7%	± 5.1 %
2500	123.7	120.7	-2.4%	121.9	-1.5%	± 5.1 %
3000	78.8	74.8	-5.0%	76.1	-3.5%	± 5.1 %
3500	256.3	248.1	-3.2%	246.0	-4.0%	± 5.1 %
3700	249.7	239.2	-4.2%	239.0	-4.3%	± 5.1 %
5200	50.7	50.7	-0.1%	51.2	0.9%	± 5.1 %
5500	49.6	48.9	-1.5%	48.7	-1.9%	± 5.1 %
5800	48.9	49.1	0.4%	49.3	0.8%	± 5.1 %

**Calibration Results for Modulation Response** 

UID	Communication System Name		A dB	B dB√μV	С	D dB	VR mV	Max dev.	Unc <sup>⊨</sup> (k=2)
0	CW	Х	0.0	0.0	1.0	0.00	141.5	+ 3.3 %	± 4.7 %
		Υ	0.0	0.0	1.0		125.6		
		Υ	0.0	0.0	1.0		125.1		

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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<sup>&</sup>lt;sup>8</sup> Numerical linearization parameter: uncertainty not required.

E Uncertainty is determined using the max, deviation from linear response applying rectangular distribution and is expressed for the square of the

# DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

## **Sensor Frequency Model Parameters**

	Sensor X	Sensor Y	Sensor Z
Frequency Corr. (LF)	0.28	0.21	5.68
Frequency Corr. (HF)	2.82	2.82	2.82

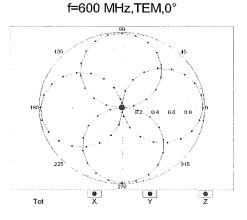
#### Other Probe Parameters

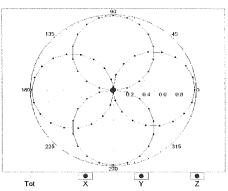
Sensor Arrangement	Rectangular
Connector Angle (°)	57.9
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	12 mm
Tip Length	25 mm
Tip Diameter	4 mm
Probe Tip to Sensor X Calibration Point	1.5 mm
Probe Tip to Sensor Y Calibration Point	1.5 mm
Probe Tip to Sensor Z Calibration Point	1.5 mm

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# Receiving Pattern ( $\phi$ ), $\vartheta = 0^{\circ}$

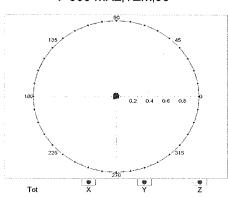




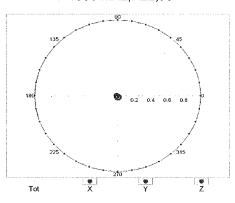
f=1800 MHz,R22,0°

# Receiving Pattern ( $\phi$ ), $\vartheta = 90^{\circ}$

f=600 MHz,TEM,90°



## f=1800 MHz,R22,90°

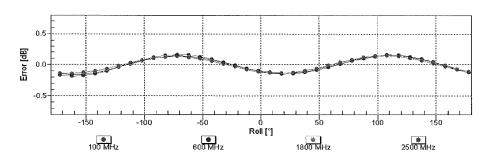


Certificate No: EF3-4035\_Jan19/2

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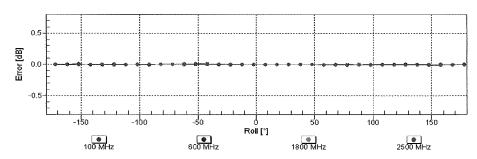
FCC ID: A3LSMA716U	POTEST:	HAC (RF EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dags 62 of 90
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# Receiving Pattern ( $\phi$ ), $\vartheta = 0^{\circ}$



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

# Receiving Pattern ( $\phi$ ), $\vartheta = 90^{\circ}$



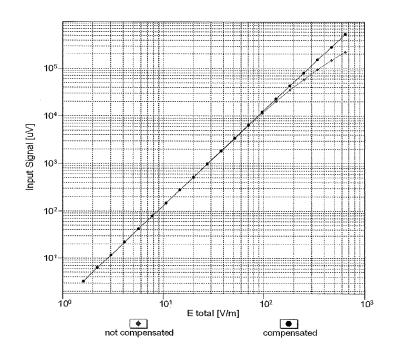
Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

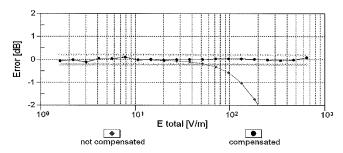
Certificate No: EF3-4035\_Jan19/2

FCC ID: A3LSMA716U	POTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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# Dynamic Range f(E-field) (TEM cell, f = 900 MHz)





Uncertainty of Linearity Assessment: ± 0.6% (k=2)

0-4/0-1- No. FFO 4005 (-40/0

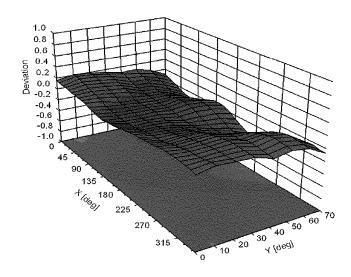
Certificate No: EF3-4035\_Jan19/2 Page 7 of 8

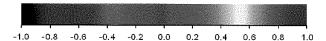
FCC ID: A3LSMA716U	PCTEST	HAC (RE EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 65 of 89
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# Deviation from Isotropy in Air Error $(\phi, \vartheta)$ , f = 900 MHz





Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

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Client

**PC Test** 

Accreditation No.: SCS 0108

Certificate No: CD835V3-1003\_Feb19

#### CALIBRATION CERTIFICATE CD835V3 - SN: 1003 Object Calibration procedure(s) **QA CAL-20.v7** Calibration Procedure for Validation Sources in air 3/19/2019 Calibration date: February 19, 2019 This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature ( $22 \pm 3$ )°C and humidity < 70%. Calibration Equipment used (M&TE critical for calibration) Primary Standards ID# Cal Date (Certificate No.) Scheduled Calibration Power meter NRP SN: 104778 04-Apr-18 (No. 217-02672/02673) Apr-19 Power sensor NRP-Z91 SN: 103244 04-Apr-18 (No. 217-02672) Apr-19 Power sensor NRP-Z91 SN: 103245 04-Apr-18 (No. 217-02673) Apr-19 Reference 20 dB Attenuator SN: 5058 (20k) 04-Apr-18 (No. 217-02682) Apr-19 Type-N mismatch combination SN: 5047.2 / 06327 04-Apr-18 (No. 217-02683) Apr-19 Probe EF3DV3 SN: 4013 03-Jan-19 (No. EF3-4013\_Jan19) Jan-20 DAE4 SN: 781 09-Jan-19 (No. DAE4-781\_Jan19) Jan-20 Secondary Standards ID# Check Date (in house) Scheduled Check Power meter Agilent 4419B SN: GB42420191 09-Oct-09 (in house check Oct-17) In house check: Oct-20 Power sensor HP E4412A SN: US38485102 05-Jan-10 (in house check Oct-17) In house check: Oct-20 Power sensor HP 8482A SN: US37295597 09-Oct-09 (in house check Oct-17) In house check: Oct-20 RF generator R&S SMT-06 SN: 832283/011 27-Aug-12 (in house check Oct-17) In house check: Oct-20 Network Analyzer HP 8358A SN: US41080477 31-Mar-14 (in house check Oct-18) In house check: Oct-19 Name Function Calibrated by: Claudio Leubler Laboratory Technician Approved by: Katja Pokovic Technical Manager Issued: February 20, 2019 This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: CD835V3-1003\_Feb19

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FCC ID: A3LSMA716U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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#### References

ANSI-C63.19-2011
 American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids,

#### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna
  (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes.
  In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a
  distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
  figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
  is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
  directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network
  Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was
  eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
  obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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 FCC ID: A3LSMA716U
 PCTEST
 HAC (RF EMISSIONS) TEST REPORT
 Approved by: Quality Manager

 Filename:
 Test Dates:
 DUT Type:

 1M2003200047-02-R1.A3L
 4/27/2020 - 4/29/2020
 Portable Handset

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### **Measurement Conditions**

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.2
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	835 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

### Maximum Field values at 835 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	105.2 V/m = 40.44 dBV/m	
Maximum measured above low end	100 mW input power	105.1 V/m = 40.43 dBV/m	
Averaged maximum above arm	100 mW input power	105.2 V/m ± 12.8 % (k=2)	

# Appendix (Additional assessments outside the scope of SCS 0108)

#### **Antenna Parameters**

Frequency	Return Loss	Impedance 40.4 Ω - 7.2 jΩ	
800 MHz	17.6 dB		
835 MHz	25.8 dB	52.2 Ω + 4.7 jΩ	
880 MHz	16.9 dB	62.1 Ω - 10.5 jΩ	
900 MHz	16.9 dB	52.2 Ω - 14.6  Ω	
945 MHz	21.6 dB	51.8 Ω + 8.3 ϳΩ	

### 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

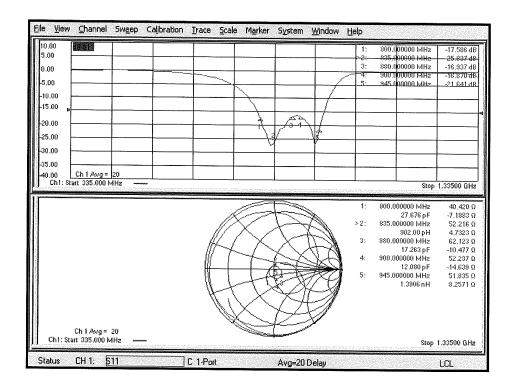
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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FCC ID: A3LSMA716U	HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
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### **Impedance Measurement Plot**



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#### **DASY5 E-field Result**

Date: 19.02.2019

Test Laboratory: SPEAG Lab2

#### DUT: HAC-Dipole 835 MHz; Type: CD835V3; Serial: CD835V3 - SN: 1003

Communication System: UID 0 - CW ; Frequency: 835 MHz Medium parameters used:  $\sigma=0$  S/m,  $\epsilon_r=1$ ;  $\rho=0$  kg/m³ Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY52 Configuration:

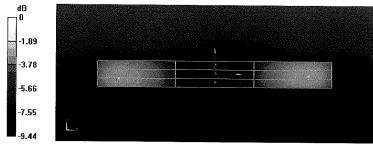
- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 835 MHz; Calibrated: 03.01.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 09.01.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.2(1495); SEMCAD X 14.6.12(7450)

## Dipole E-Field measurement @ 835MHz/E-Scan - 835MHz d=15mm/Hearing Aid Compatibility Test (41x361x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 127.3 V/m; Power Drift = 0.04 dB Applied MIF = 0.00 dB RF audio interference level = 40.44 dBV/m Emission category: M3

MIF scaled E-field

Grid 1 <b>M4</b>	Grid 2 <b>M3</b>	Grid 3 M3
39.75 dBV/m	40.43 dBV/m	40.43 dBV/m
Grid 4 M4	Grid 5 <b>M4</b>	Grid 6 <b>M4</b>
35.35 dBV/m	35.75 dBV/m	35.73 dBV/m
Grid 7 <b>M3</b>	Grid 8 <b>M3</b>	Grid 9 <b>M3</b>
40.15 dBV/m	40.44 dBV/m	40.36 dBV/m



0 dB = 105.2 V/m = 40.44 dBV/m

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Accreditation No.: SCS 0108

Client PC Test

Certificate No: CD1880V3-1137\_Feb19

CALIBRATION	CERTIFICAT	E		
Object	CD1880V3 - SN	1: 1137		
Calibration procedure(s)	QA CAL-20.v7 Calibration Proc	edure for Validation Sources in a	ir	/0 3/19/
Calibration date:	February 19, 20	19		
All calibrations have been conduc	ertainties with confidence p	tional standards, which realize the physical ur probability are given on the following pages are pry facility: environment temperature $(22 \pm 3)^{\circ}$	nd are part of the certificate.	
Calibration Equipment used (M&T Primary Standards	ID #	0.15.4 (5.11)		
Power meter NRP	SN: 104778	Cal Date (Certificate No.)	Scheduled Calibration	
Ower sensor NRP-Z91	SN: 104778 SN: 103244	04-Apr-18 (No. 217-02672/02673)	Apr-19	
ower sensor NRP-Z91	SN: 103244	04-Apr-18 (No. 217-02672)	Apr-19	
Reference 20 dB Attenuator		04-Apr-18 (No. 217-02673)	Apr-19	
ype-N mismatch combination	SN: 5058 (20k) SN: 5047.2 / 06327	04-Apr-18 (No. 217-02682)	Apr-19	
robe EF3DV3	SN: 4013	04-Apr-18 (No. 217-02683)	Apr-19	
DAE4	SN: 781	03-Jan-19 (No. EF3-4013_Jan19) 09-Jan-19 (No. DAE4-781_Jan19)	Jan-20 Jan-20	
Secondary Standards	ID#	Check Date (in house)	Scheduled Check	
ower meter Agilent 4419B	SN: GB42420191	09-Oct-09 (in house check Oct-17)	In house check: Oct-20	
ower sensor HP E4412A	SN: US38485102	05-Jan-10 (in house check Oct-17)	In house check: Oct-20	
ower sensor HP 8482A	SN: US37295597	09-Oct-09 (in house check Oct-17)	In house check; Oct-20	
F generator R&S SMT-06	SN: 832283/011	27-Aug-12 (in house check Oct-17)	In house check: Oct-20	
etwork Analyzer HP 8358A	SN: US41080477	31-Mar-14 (in house check Oct-18)	In house check: Oct-19	
	Name	Function	Ciprotuvo	
alibrated by:	Claudio Leubler	Laboratory Technician	Signature	
		Educatory recinical		
,				
-	Katja Pokovic	Technical Manager		
pproved by:	Katja Pokovic	Technical Manager	My	

Certificate No: CD1880V3-1137\_Feb19

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FCC ID: A3LSMA716U	POTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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#### References

[1] ANSI-C63.19-2011 American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna
  (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes.
  In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a
  distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
  figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
  is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
  directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network
  Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was
  eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
  obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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FCC ID: A3LSMA716U	PCTEST:	HAC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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Certificate No: CD1880V3-1137\_Feb19

REV 3.5.M

### **Measurement Conditions**

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.2
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	1730 MHz ± 1 MHz 1880 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

### Maximum Field values at 1730 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	95.0 V/m = 39.55 dBV/m
Maximum measured above low end	100 mW input power	94.9 V/m = 39.55 dBV/m
Averaged maximum above arm	100 mW input power	95.0 V/m ± 12.8 % (k=2)

### Maximum Field values at 1880 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	88.9 V/m = 38.98 dBV/m
Maximum measured above low end	100 mW input power	86.6 V/m = 38.75 dBV/m
Averaged maximum above arm	100 mW input power	87.8 V/m ± 12.8 % (k=2)

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### Appendix (Additional assessments outside the scope of SCS 0108)

### **Antenna Parameters**

#### **Nominal Frequencies**

Frequency	Return Loss	Impedance
1730 MHz	22.5 dB	54.4 Ω + 6.5 jΩ
1880 MHz	21.1 dB	55.9 Ω + 7.2 jΩ
1900 MHz	21.0 dB	59.0 Ω + 3.6 jΩ
1950 MHz	27.3 dB	53.0 Ω - 3.3 jΩ
2000 MHz	20.3 dB	42.4 Ω + 4.8 jΩ

### 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

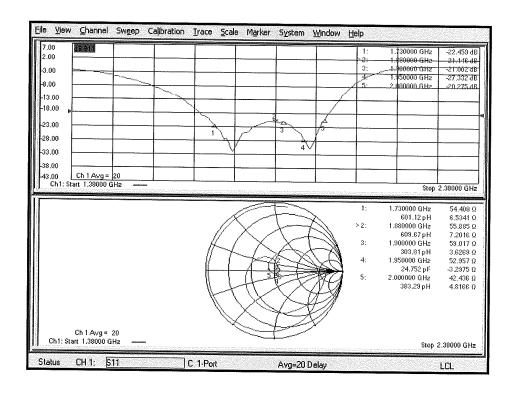
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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### **Impedance Measurement Plot**



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#### **DASY5 E-field Result**

Date: 19.02.2019

Test Laboratory: SPEAG Lab2

# DUT: HAC Dipole 1880 MHz; Type: CD1880V3; Serial: CD1880V3 - SN: 1137

Communication System: UID 0 - CW ; Frequency: 1880 MHz, Frequency: 1730 MHz Medium parameters used:  $\sigma=0$  S/m,  $\epsilon_r=1$ ;  $\rho=0$  kg/m³ Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY52 Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 1880 MHz, ConvF(1, 1, 1) @ 1730 MHz; Calibrated: 03.01.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 09.01.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.2(1495); SEMCAD X 14.6.12(7450)

# Dipole E-Field measurement @ 1880MHz/E-Scan - 1880MHz d=15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 151.5 V/m; Power Drift = 0.02 dB Applied MIF = 0.00 dB RF audio interference level = 38.98 dBV/m Emission category: M2

#### MIF scaled E-field

Grid 1 <b>M2</b>	Grid 2 <b>M2</b>	Grid 3 <b>M2</b>
38.55 dBV/m	38.98 dBV/m	38.93 dBV/m
Grid 4 <b>M2</b>	Grid 5 M2	Grid 6 <b>M2</b>
35.71 dBV/m	35.97 dBV/m	35.96 dBV/m
Grid 7 <b>M2</b>	Grid 8 <b>M2</b>	Grid 9 <b>M2</b>
38.31 dBV/m	38.75 dBV/m	38.73 dBV/m

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# Dipole E-Field measurement @ 1880MHz /E-Scan - 1730MHz d=15mm/Hearing Aid Compatibility Test (41x181x1);

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 165.0 V/m; Power Drift = 0.03 dB

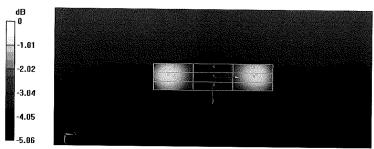
Applied MIF = 0.00 dB

RF audio interference level = 39.55 dBV/m

Emission category: M2

### MIF scaled E-field

Grid 1 M2	Grid 2 <b>M2</b>	Grid 3 M2
39.09 dBV/m	39.55 dBV/m	39.51 dBV/m
Grid 4 <b>M2</b>	Grid 5 <b>M2</b>	Grid 6 M2
36.57 dBV/m	36.95 dBV/m	36.95 dBV/m
Grid 7 M2	Grid 8 <b>M2</b>	Grid 9 <b>M2</b>
39.05 dBV/m	39.55 dBV/m	39.53 dBV/m



0 dB = 88.87 V/m = 38.98 dBV/m

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### **Calibration Laboratory of**

Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland





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Client

PC Test

Certificate No: CD2600V3-1012 Feb19

Object	CD2600V3 - SN	: 1012	
Calibration procedure(s)	QA CAL-20.v7 Calibration Proce	edure for Validation Sources in al	ir 10A 3/19/20
Calibration date:	February 19, 20	19	
The measurements and the unce	ertainties with confidence p	ional standards, which realize the physical un orobability are given on the following pages ar ny facility: environment temperature (22 $\pm$ 3)°0	nd are part of the certificate.
Calibration Equipment used (M&			
Primary Standards	ID#	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	04-Apr-18 (No. 217-02672/02673)	Apr-19
Power sensor NRP-Z91	SN: 103244	04-Apr-18 (No. 217-02672)	Apr-19
Power sensor NRP-Z91	SN: 103245	04-Apr-18 (No. 217-02673)	Apr-19
Reference 20 dB Attenuator	SN: 5058 (20k)	04-Apr-18 (No. 217-02682)	Apr-19
Type-N mismatch combination	SN: 5047.2 / 06327	04-Apr-18 (No. 217-02683)	Apr-19
Probe EF3DV3	SN: 4013	03-Jan-19 (No. EF3-4013_Jan19)	Jan-20
DAE4	SN: 781	09-Jan-19 (No. DAE4-781_Jan19)	Jan-20
Secondary Standards	ID#	Check Date (in house)	Scheduled Check
Power meter Agilent 4419B	SN: GB42420191	09-Oct-09 (in house check Oct-17)	In house check: Oct-20
Power sensor HP E4412A	SN: US38485102	05-Jan-10 (in house check Oct-17)	In house check; Oct-20
Power sensor HP 8482A	SN: US37295597	09-Oct-09 (in house check Oct-17)	In house check; Oct-20
RF generator R&S SMT-06	SN: 832283/011	27-Aug-12 (in house check Oct-17)	In house check: Oct-20
Network Analyzer HP 8358A	SN: US41080477	31-Mar-14 (in house check Oct-18)	In house check: Oct-19
Callbratad b	Name	Function	Signature
Calibrated by:	Claudio Leubler	Laboratory Technician	VXA
Approved by:	Katja Pokovic	Technical Manager	Cliff

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Accreditation No.: SCS 0108

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#### References

ANSI-C63.19-2011 [1] American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

#### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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#### **Measurement Conditions**

DASY system configuration, as far as not given on page 1

DASY Version	DASY5	V52.10.2
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	2600 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

### Maximum Field values at 2600 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	85.6 V/m = 38.65 dBV/m	
Maximum measured above low end	100 mW input power	84.7 V/m = 38.56 dBV/m	
Averaged maximum above arm	100 mW input power	85.2 V/m ± 12.8 % (k=2)	

# Appendix (Additional assessments outside the scope of SCS 0108)

#### **Antenna Parameters**

Frequency	Return Loss	Impedance
2450 MHz	20.5 dB	42.7 Ω - 4.8 jΩ
2550 MHz	32.1 dB	48.9 Ω + 2.2 jΩ
2600 MHz	39.6 dB	50.3 Ω + 1.0 jΩ
2650 MHz	30.4 dB	$53.0 \Omega + 0.9 j\Omega$
2750 MHz	20.9 dB	48.9 Ω - 8.9 ϳΩ

### 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

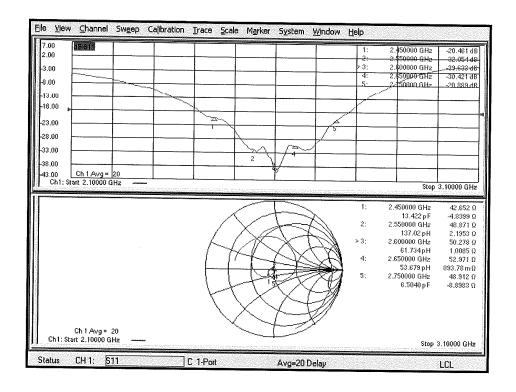
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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### **Impedance Measurement Plot**



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### **DASY5 E-field Result**

Date: 19.02.2019

Test Laboratory: SPEAG Lab2

### DUT: HAC Dipole 2600 MHz; Type: CD2600V3; Serial: CD2600V3 - SN: 1012

Communication System: UID 0 - CW ; Frequency: 2600 MHz Medium parameters used:  $\sigma=0$  S/m,  $\epsilon_r=1$ ;  $\rho=0$  kg/m $^3$  Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY52 Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 2600 MHz; Calibrated: 03.01.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 09.01.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.2(1495); SEMCAD X 14.6.12(7450)

# Dipole E-Field measurement @ 2600MHz - with/E-Scan - 2600MHz d=15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 62.82 V/m; Power Drift = -0.01 dB

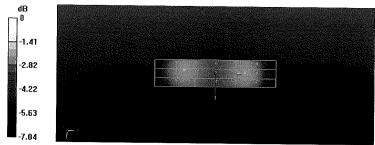
Applied MIF = 0.00 dB

RF audio interference level = 38.65 dBV/m

Emission category: M2

### MIF scaled E-field

Grid 1 <b>M2</b>	Grid 2 <b>M2</b>	Grid 3 <b>M2</b>
38.09 dBV/m	38.56 dBV/m	38.54 dBV/m
Grid 4 M2	Grid 5 <b>M2</b>	Grid 6 <b>M2</b>
37.82 dBV/m	38.06 dBV/m	38.02 dBV/m
Grid 7 <b>M2</b>	Grid 8 <b>M2</b>	Grid 9 <b>M2</b>
38.36 dBV/m	38.65 dBV/m	38.56 dBV/m



0 dB = 85.60 V/m = 38.65 dBV/m

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# 16. CONCLUSION

The measurements taken in accordance with the procedures provided in the CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017, indicate that the wireless communications device complies with the HAC limits specified in the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

Please note that the M-rating for this equipment only represents the field interference possible against a hypothetical and typical hearing aid. The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

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